

A Multiscale Investigation into the Electroplastic Effects in Copper: Experiments and Crystal Plasticity Modeling

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Abstract

Electroplastic effects in metals show measurable changes of exerted force in deformation processes under certain electric current conditions, holding potential to facilitate metal forming. However, the application of these effects is hindered by the so far unclear image of the underlying mechanisms, and the corresponding contributions are debatable. This work aims to quantitatively elucidate the athermal mechanisms of electroplasticity in copper with experimental and computational methods combined. Temperature-controlled pulsed-current electricity-assisted deformation (EAD) tests were conducted to emphasize athermal contributions, while large-area EBSD, two-beam TEM, and high-resolution EBSD (HR-EBSD) measurements were used to characterize texture evolution, slip systems, and semi-quantitative dislocation density. Then, a crystal plasticity model, incorporating electroplasticity-related mechanisms with thermodynamic evolution formulas, was applied to support a mechanism-focused interpretation of the observed electroplastic responses from dislocation behaviors. Analysis reveals that the reduced work hardening observed in the stress-strain curves originates from fluctuations in the local response. These fluctuations exhibit a characteristic two-stage behavior, consisting of an “rapid drop” followed by a “slow decline” of stress response. The associated changes in maximum flow stress and macroscopic work-hardening rate arise from the cumulative effect of EAD-induced softening during current pulses, which is linked to the recovery of statistically stored dislocations (SSDs). By quantitatively connecting short-term information to macroscopic stress-strain evolution within an

1 electricity-coupled crystal plasticity framework and comparing with experimental textures and
2 dislocation densities, this work provides mechanistic interpretations of athermal mechanisms and
3 consolidate the understanding of electroplasticity in metals.

4 **Keywords: Electroplasticity, Electricity-assisted deformation, Athermal effect, Electricity-coupled**
5 **crystal plasticity, Dislocation recovery.**

7 1. Introduction

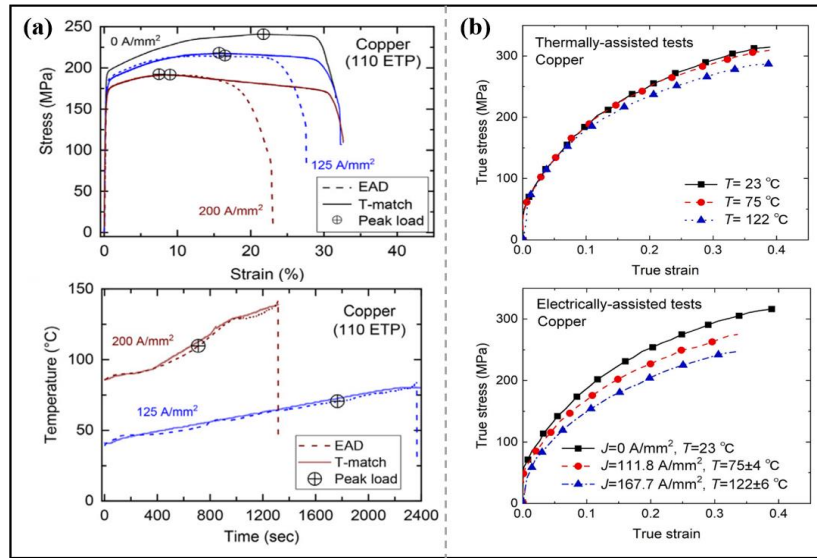
8 Electroplastic effects during electricity-assisted deformation (EAD) have long been recognized for
9 their potential to tailor mechanical properties (Ruszkiewicz et al., 2017). By applying alternating (AC)
10 or direct current (DC) during metal forming, flow stress reductions (He et al., 2020; Ruszkiewicz et al.,
11 2017; Xu et al., 2022; Zhang et al., 2018), changes in the maximum elongation (He et al., 2020; Li et
12 al., 2022a; Xu et al., 2022; Zhang et al., 2018; Zhao et al., 2021), and variations in work-hardening rate
13 (Kim et al., 2017; Xu et al., 2022; Zhao et al., 2021) have been reported. These effects have
14 practical applications for processes such as thin-wall structure forming and forging (Jones and Mears,
15 2011; Jones et al., 2012; Li et al., 2022a; Siopis et al., 2011). Therefore, understanding the
16 underlying physics of electroplastic effects is crucial for designing and optimizing EAD-assisted
17 manufacturing processes.

18 Electroplasticity during EAD is driven by multiple mechanisms, including Joule heating and
19 athermal effects arising from electron-dislocation interactions or other electric-field-induced
20 processes. While Joule heating has been widely invoked to explain stress drops in metals such as steels
21 (Tang et al., 2000), titanium alloys (Dimitrov et al., 2021; Kinsey et al., 2013; Lee et al., 2017) and
22 copper (He et al., 2020)(Xu et al., 2022; Zhang et al., 2018), however, recent studies demonstrate that
23 electric current can also directly modify dislocation activity, enhance ductility, or alter flow stress
24 independent of measurable temperature rise (Chuan et al., 2024; Niu et al., 2025; Zhao et al., 2021).
25 Decoupling these effects is usually challenging, as thermal, electromagnetic, and stress field are
26 coupled together. Endeavors have been made to decouple these effects.

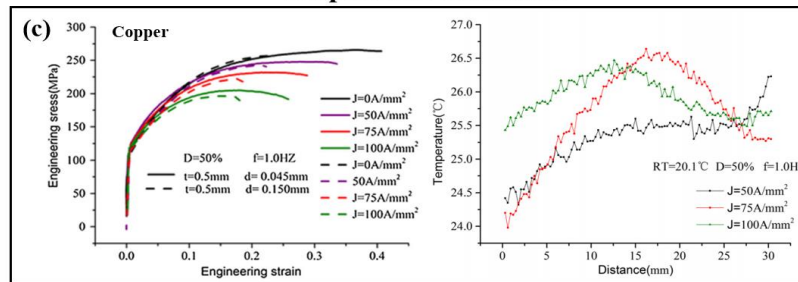
27 On theoretical side, researchers proposed diverse propositions. The electron wind force, acting
28 proportionally to the value of current density, exert additional driving force on dislocation motion (Ren
29 and Wang, 2025; Xu et al., 2023) . Others proposed electron-dislocation scattering (Dai et al., 2024; Li
30 et al., 2013; Xu et al., 2023) as mechanism, which is proposed as energy transfer to dislocation core
31 area and thus lower the corresponding energy barrier for dislocation evolution. In addition, the
32 magnetoplastic effect exist in metals and suggest that current-induced magnetic fields can also
33 enhance dislocation mobility (Aksenova et al., 2022; Alshits et al., 1997; Molotskii and Fleurov,
34 1997a, b; Molotskii, 2000). On experimental side, experiments on incoherent twinning boundaris
35 (ITBs) (Li et al., 2022c) and mechanical tests on e-beam irradiated Au foils (Stangebye et al., 2022)
36 suggested electron-dislocation scattering as the key mechanism, while electricity-coupled Ni single-
37 crystal (Li et al., 2022b) and Ni alloy (Zhang et al., 2020) tests are in favour of the electron-wind
38 force. Under electro-magnetic field, experimental studies have also proposed significant magnetoplastic
39 effects existing in metals (Aksenova et al., 2022; Guo et al., 2022; Jemielniak and Krolkowski,
40 1985; Yang et al., 2023b). In general, a multitude of potential electroplastic mechanisms exist, each
exerting distinct influences on dislocation dynamics and contributing to varying degrees to the specific
mechanical response.

1 The complexity of the mechanisms makes the discussions conflict in published reports. Taking
 2 copper as an example, pure copper shows significant flow stress reduction (Fig. 1(b-c)) and texture
 3 evolution under some conditions (Fig. 1(d)), while other studies report negligible or opposite trends
 4 (Fig. 1(a, e)) (Chuan et al., 2024; Dimitrov et al., 2021; Lee et al., 2017; Niu et al., 2025; Zhang et al.,
 5 2018). Subtle stress-strain fluctuations are often overlooked due to low temporal resolution,
 6 which contains information on electroplastic mechanisms. These inconsistencies emphasize the
 7 need for controlled experiments to decouple thermal and athermal effects. Copper, with high
 8 electrical and thermal conductivity (Lu et al., 2004), is an ideal model. Careful pulsed-current
 9 design and cooling keep temperature rise minimal (~few K) (He et al., 2020; Rudolf et al., 2021;
 10 Zhang et al., 2018), ensuring observed responses primarily reflect athermal mechanisms and justifying
 11 the experimental design in this study.

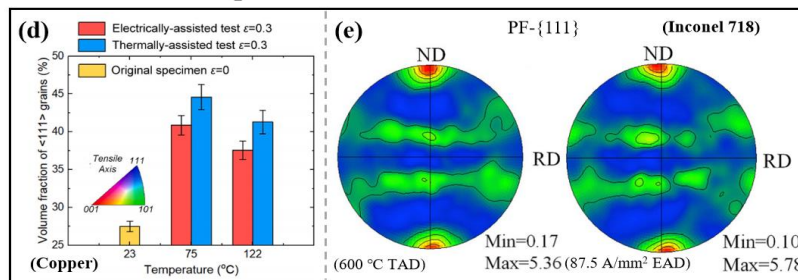
Mechanical response difference between EAD and TAD



Pulsed electricity effects on mechanical response with temperature controlled



Texture components difference between EAD and TAD



12

13 **Fig. 1** Reports on electroplasticity in copper (a-d) and Inconel 718 (e). (a-b) Stress response differences

1 between electricity-aided deformation (EAD) under various current intensities and profiles and
2 thermally-assisted deformation (TAD) tests with matched temperature (Rudolf et al., 2021; Xu et al.,
3 2022) (c) Mechanical behavior during pulsed EAD with temperature controlled (Zhang et al., 2018) (d)
4 Comparative analysis of $\langle 111 \rangle$ component intensity in deformed textures corresponding to processes
5 depicted in (b) (Xu et al., 2022). (e) Pole figures illustrating deformed textures under EAD and TAD
6 with equivalent temperature conditions (Liu et al., 2022).

7 Numerical modeling is indispensable for uncovering electroplastic mechanisms, as completely in-situ
8 characterization is usually difficult under varying electromagnetic fields present in the samples. Discrete
9 dislocation dynamics (DDD) simulations capture microscale mechanisms (Xu et al., 2023) but lack
10 direct multiscale validation. Crystal plasticity finite element methods (CPFEM) have been effective for
11 small deformations ($\sim 2\%$ strain) (Lahiri et al., 2019; Yang et al., 2023a), yet their application to
12 industrial-scale pulsed-current electrically assisted deformation (EAD) faces significant computational
13 challenges (Xu et al., 2022) due to the need for extremely small time increments and repeated
14 integration within each current pulse. As a result, most large-strain CPFEM studies are restricted to one
15 or two pulses or assume steady current conditions (Gao et al., 2022; Tiwari et al., 2022; Zheng and Yi,
16 2025). Macroscopic models, such as modified Kocks-Mecking formulations (Dai et al., 2024; Niu et al.,
17 2025) capture overall stress responses but cannot resolve texture evolution or quantitative dislocation
18 density changes. To bridge this gap, the dislocation density-based elastic visco-plastic self-consistent
19 (EVPSC) framework offers an effective compromise, enabling simultaneous prediction of mechanical
20 response, dislocation evolution, and texture development with manageable computational cost
21 (Lebensohn and Tomé, 1993; Wang et al., 2017; Wang et al., 2010; Zhu et al., 2021). In the present
22 work, combining pulsed EAD experiments results with an electricity-coupled EVPSC model provides a
23 mechanism-oriented study for interpreting large-strain electroplastic deformation.

24 In this study, we investigate the athermal mechanisms of electroplasticity in copper using a combined
25 strategy that integrates temperature-controlled pulsed EAD experiments with an electricity-coupled,
26 dislocation-based crystal plasticity model. Experiments serve to constrain and validate the constitutive
27 model description, enabling quantitative assessment of dislocation-level mechanisms at different
28 deformation stages. This integrated approach provides a unified physical interpretation of electroplastic
29 responses and reconciles previously debated observations in the literature.

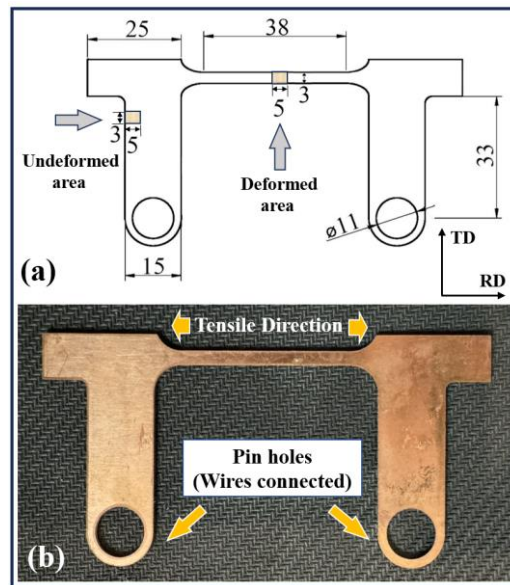
30 For clarity, the organization of this paper is as follows. Section 2 describes the experimental setup and
31 loading parameters for the EAD tests, together with the basic material characterization procedures.
32 Section 3 presents the theoretical framework of the electricity-coupled crystal plasticity model. In
33 Section 4, we first provide analysis of the mechanical responses and microstructural characterization
34 results, then calibrate the crystal plasticity model against experiments and validate it. Finally use
35 the multiscale information obtained from the model to further elucidate the deformation mechanisms
36 governing EAD.

37 38 39 **2. Materials and experiment results**

40 **2.1. Material and sample preparation**

41 The samples used in this study were fabricated from rolled industrially pure copper sheets with a
42 nominal composition of 99.9% Cu. All specimens were sectioned from the same sheet to ensure
consistency in material provenance. The detailed configuration of the cut samples is demonstrated in
Fig.

1 2, showing a “two-ear” dog-bone shaped characteristic with a thickness of 1mm. All cut copper
2 specimens were annealed at 450 °C for 1 hour.

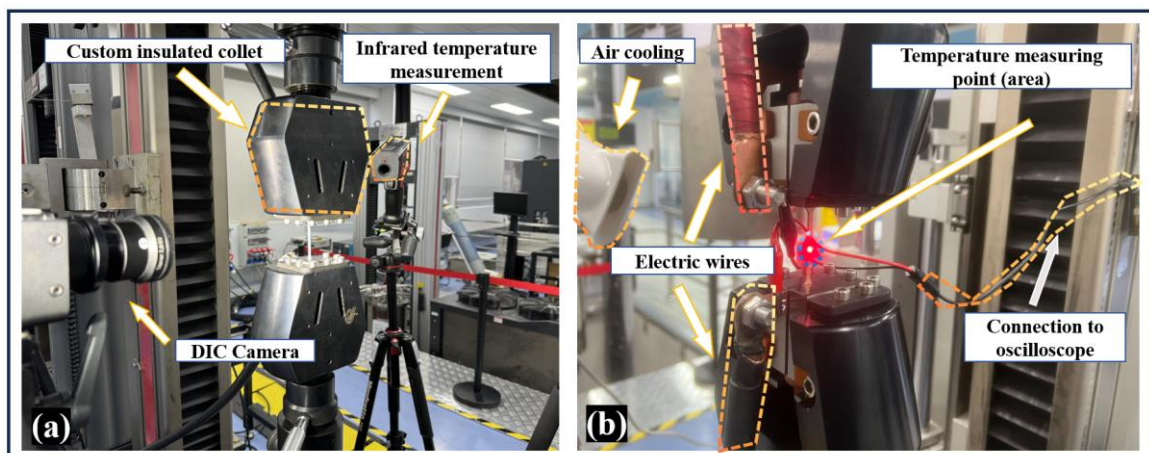


3

4 **Fig. 2** (a) Geometric graph and (b) photo of the electricity-aided tensile test sample with pin holes
5 connected to the electricity wires. EBSD samples are chosen from the undeformed area and the
6 deformed area shown in (a). Tension tests were performed along RD.

7 2.2. Tensile test setup

8 Mechanical experiments were carried out on a custom-designed platform (Fig. 3) built on a standard
9 ZwickRoell tensile machine, equipped with phenolic-resininsulated collets to prevent electrical damage
10 under high current. To investigate the athermal effect of electricity, specimen temperature was strictly
11 controlled: a chilled-air cooling unit was continuously operated about 15 cm from the sample, while
12 surface temperature was monitored in real time with a laser-calibrated infrared thermometer (TASI
13 Electronics Co., Ltd.) to capture temperature fluctuations. The measure resolution of machine has been
14 analyzed to be ± 0.035 MPa (see in Appendix 4).



15

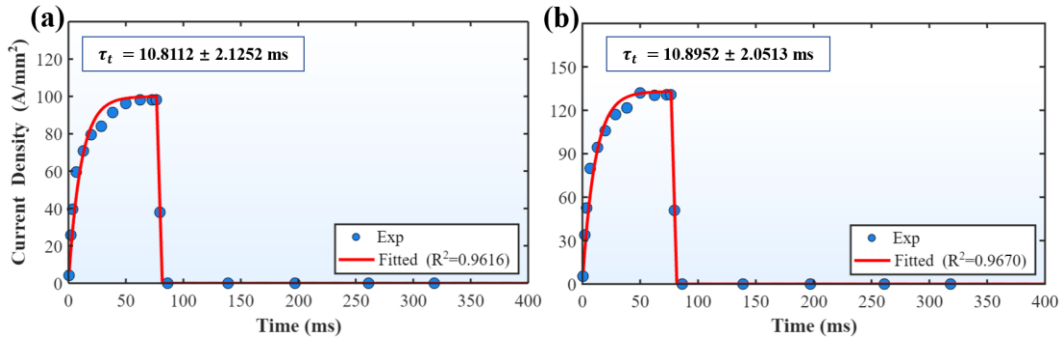
16 **Fig. 3** Experimental setup for electricity-assisted tensile testing, featuring a custom insulated collet,

1 infrared temperature measurement, chilled-air cooling, and an oscilloscope connected to the sample.

2 Current densities of 100 A/mm² and 133 A/mm² were applied at 2.5 Hz with a 20% duty time, chosen
3 to minimize heating and enable reproducible simulations. The temporal current waveforms (Fig. 4)
4 exhibit capacitive charging behavior, well fitted by a classical exponential function (as presented in Eq.
5 (1)) (Fig. 4) and subsequently used in simulations.

$$6 \quad J(t) = J_{max} \left[1 - \exp\left(\frac{-(t + \Delta t)}{\tau_t}\right) \right], \quad nT < t < (n + 0.2)T \quad (1)$$

7 where J_{max} refers to the applied current density and τ_t refers to the characteristic time of a charging
8 process and Δt is the temporal phase difference. During tensile tests, all samples were deformed at a
9 constant engineering strain rate of $5 \times 10^{-3} \text{ s}^{-1}$, with a maximum engineering strain of 0.3, prior to the
10 fracture strain (~ 0.4) of similar samples (Xu et al., 2022). Each tensile test contains 150 cycles of pulses
11 with a duration of 60 seconds. All EAD tests were conducted with real-time compliance correction and a
12 control frequency of 1000 Hz (control cycle ≈ 1 ms), sufficient to maintain constant strain rate during
13 the electricity working time (80 ms). The sample temperatures were controlled close to ambient (~ 296
14 K) throughout all tensile tests. The detailed demonstration of the temperature evolution is provided in
15 the Supplementary Materials.



17 **Fig. 4** (a-b) Charging current waveform at 100 A/mm² and 133 A/mm², 20% duty ratio.

18 2.3. Microstructure measurements

19 After the electro-mechanical coupling experiments, the microstructure was characterized using
20 electron backscatter diffraction (EBSD) and transmission electron microscopy (TEM). EBSD analysis
21 was performed on undeformed and deformed regions (Fig. 2a) using a system from EDAX Inc. (USA).
22 Specimens were electro-polished in a phosphoric acid–ethanol solution (1:9 by volume) at -20 °C under
23 28 V and 0.9 A for 30 s. Scans were conducted over a $1000 \mu\text{m} \times 1000 \mu\text{m}$ area with a $1 \mu\text{m}$ step size to
24 obtain statistically significant information on textures and grain sizes. Kernel average misorientation
25 (KAM) was analyzed to assess geometrically necessary dislocations (GNDs) with and without electrical
26 current. TEM specimens were prepared by ion milling. Disc-shaped samples (3 mm diameter) were
27 sectioned via wire EDM, mechanically ground to $\sim 25 \mu\text{m}$, mounted on copper grids, and thinned using a
28 Gatan Model 691 ion milling system. Final perforation was conducted at 4 kV, followed by polishing at
29 3 kV for 30 min. TEM observations were performed using an FEI Talos F200X G2 microscope (FEI,
30 USA).

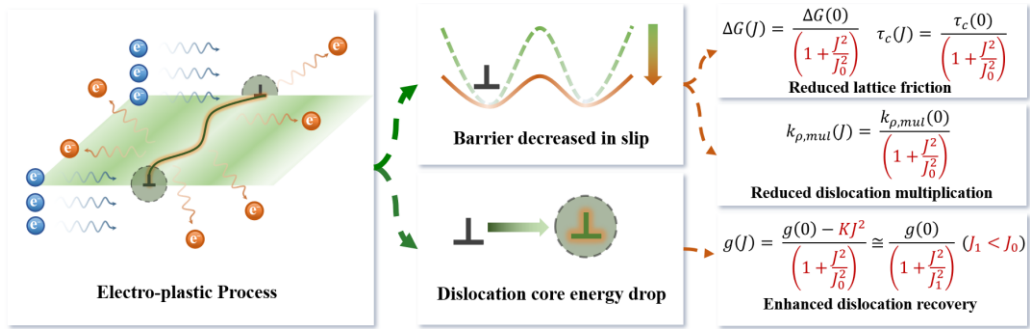
31 Dislocation density evolution was further investigated using high-resolution EBSD (HR-EBSD),
32 following a Williamson-Hall-plot method (Borbély, 2022) (see details in SM Part 1). HR-EBSD was

1 conducted on undeformed and deformed regions subjected to 100 A/mm² current, covering 200 μm ×
 2 200 μm areas with ~40,000 Kikuchi patterns collected at 1 μm step size and 128 × 156 pixels resolution.
 3 Diffraction peak widths from experimental patterns were compared with simulations to estimate relative
 4 dislocation densities. Experiments utilized an Oxford Instruments C-Swift EBSD camera, allowing
 5 quantification of GNDs (ρ_{GND}) and total dislocation density (ρ_{tot}). The ρ_{tot} increment provides a key
 6 reference for validating the EC-EVPSC model, as discussed in Section 4.3.

7 3. Self-consistent polycrystal model coupled with electricity

8 3.1. Brief description of the self-consistent polycrystalline framework

9 Crystal plasticity simulation is employed in this study to investigate the polycrystalline deformation
 10 history during EAD. This approach facilitates an interpretation of the electroplastic origin based on
 11 multiscale mechanisms, including the evolution of dislocation density, dislocation movement, and
 12 texture. Consequently, this research incorporates electroplastic effects into the well-established
 13 EVPSC framework (Beyerlein and Tomé, 2008; Sun et al., 2024; Wang et al., 2010a; Wang et al., 2010b;
 14 Zhu et al., 2021) and create the electricity-coupled elastic-viscoplastic self-consistent (EC-EVPSC)
 15 polycrystal model to capture electroplastic behavior. The present model incorporates electro-
 16 mechanical coupling effects of defects, accounting for key mechanisms such as reduced barriers for
 17 dislocation slip, reduced dislocation multiplication, and accelerated dislocation density recovery (Fig.
 18 5). The EVPSC/VPSC-based framework (Lebensohn and Tomé, 1993) describes polycrystal-grain
 19 interactions via the Eshelby tensor, bridging single-crystal slip mechanisms and macroscopic
 20 behavior. This multiscale approach effectively predicts polycrystal responses under combined elastic-
 21 viscoplastic deformations. Detailed implementation procedures are provided in Refs. (Tomé and
 22 Lebensohn, 2023; Wang et al., 2010a). A brief description of the polycrystal level self-consistent
 23 mathematical scheme is present in Appendix 1.



24
 25 **Fig. 5** Schematic representation of the athermal effects associated with electroplasticity.

26 3.2. The dislocation movements law and influences by electricity

27 In this work, the plastic deformation in each grain is the sum of dislocation-induced plasticity,
 28 calculated by summing shear strain rate tensors across multiple slip systems, where the shear strain rate
 29 in each slip system follows Orowan's equation (Orowan, 1940):

$$30 \quad l_{ij}^{dis} = \sum_{\alpha=1}^n s_i^{\alpha} n_j^{\alpha} \dot{\gamma}^{\alpha} = \sum_{\alpha=1}^n s_i^{\alpha} n_j^{\alpha} \rho^{\alpha} b^{\alpha} v^{\alpha} \quad (2)$$

31 Here, s^{α} and n^{α} represent the slip direction and normal vector of the slip plane, respectively. $\dot{\gamma}^{\alpha}$
 32 denotes the shear strain rate. ρ^{α} , b^{α} and v^{α} represent the dislocation density, Burgers vector

1 magnitude, and dislocation velocity, respectively. The slip systems considered are the conventional
 2 octahedral one in FCC metal. The Burgers vector is taken as 0.256 nm for copper (Cheong et al., 2005).
 3 The superscript α means the slip system α , similarly hereafter. The dislocation velocity is governed by
 4 the thermodynamic activation process under quasi-static loading conditions (Beyerlein and Tomé, 2008;
 5 Kocks et al., 1975; Sun et al., 2024):

$$6 \quad v^\alpha = v_0^\alpha \exp\left(\frac{-\Delta G^\alpha}{k_B T}\right) \quad (3)$$

7 where the ΔG^α denotes the free enthalpy of activation, k_B is the Boltzmann constant, and T is the
 8 absolute temperature in Kelvin. This free enthalpy will be affected when electricity is induced to the
 9 deformation process, and this effect is going to be discussed as follows in this section.

10 The activation free enthalpy, as a function, depends on the resolved shear stress on slip system α ,
 11 calculated as $\tau^\alpha = s_i^\alpha n_j^\alpha \sigma_{ij}^g$ where σ_{ij}^g is the Cauchy stress tensor in the grain coordinate system. This
 12 enthalpy can be expressed via a Taylor expansion at 0 MPa as (Beyerlein and Tomé, 2008)

$$13 \quad \Delta G^\alpha(\tau^\alpha) \cong \Delta G^\alpha(0) + \frac{\partial \Delta G^\alpha(\tau^\alpha)}{\partial \tau^\alpha} \tau^\alpha \quad (4a)$$

14 The $\frac{\partial \Delta G^\alpha(\tau^\alpha)}{\partial \tau^\alpha} = -\Delta V^{\alpha*}$ denotes the activation volume (Beyerlein and Tomé, 2008; Lahiri et al., 2019;
 15 Saada, 1995). In this work this formulation is modified to include the dislocation interaction, aligned
 16 with the expression typically employed in thermodynamic activation models (Beyerlein and Tomé, 2008;
 17 Kocks et al., 1975; Wang et al., 2013):

$$18 \quad \Delta G^\alpha(\tau_{eff}^\alpha) = \Delta G_0^\alpha - \tau_{eff}^\alpha \Delta V^{\alpha*} \quad (4b)$$

19 Here ΔG_0^α refers to the referenced Gibbs free energy and the τ_{eff}^α refers to the effective resolved shear
 20 stress, defined as $\tau_{eff}^\alpha = \tau^\alpha - \tau_f^\alpha$. τ_f^α is the friction resistance (Sun et al., 2024), primarily provided
 21 by dislocation interactions in this work (Section 3.4).

22 Equivalent to previous equations, the form adapted in previous works (Beyerlein and Tomé, 2008;
 23 Kocks et al., 1975) shows:

$$24 \quad \Delta G^\alpha(\tau_{eff}^\alpha) = \Delta G_0^\alpha \left(1 - \frac{\tau_{eff}^\alpha}{\tau_c^\alpha}\right) \quad (4c)$$

25 where τ_c^α reflects the inherent strength of the slip system. In (Beyerlein and Tomé, 2008), it has been
 26 provided a form of ΔG_0^α and $\Delta V^{\alpha*}$ as follows:

$$27 \quad \Delta G_0^\alpha = \frac{D^\alpha}{\tau_{sat}^\alpha} g^\alpha \mu b^{\alpha 3} \quad (5a)$$

$$28 \quad \Delta V^{\alpha*} = \frac{D^\alpha}{\tau_{sat}^\alpha} b^{\alpha 3} \quad (5b)$$

29 where D^α is a proportionality factor dimensionally consistent with stress, interpreted as drag stress
 30 during the dislocation movement process (Beyerlein and Tomé, 2008; Sun et al., 2024; Wang et al., 2017).
 31 g^α and μ are respectively a normalized activation energy and the macroscopic shear modulus, and τ_{sat}^α

1 is the saturated resolved shear stress. By integrating Eq. (5) into Eq. (4b) and compared with the form
 2 Eq. (4c), it appears that the following relation holds:

$$3 \quad \tau_c^\alpha = \mu g^\alpha \quad (6)$$

4 In certain prior works (Dai et al., 2024; Gao et al., 2022; Lahiri et al., 2019; Tiwari et al., 2022; Yang
 5 et al., 2023a), the effect of electric current on physical parameters has been incorporated as state variables.
 6 A similar approach is appropriate for our case, as will be illustrated through a brief magnitude estimation
 7 in the Supplementary Materials Part 3. Based on prior work, τ_c^α , which characterizes a part of the short-
 8 range barrier, is known to decrease under electric current. In this model, we adopt an analogous
 9 formulation (Lahiri et al., 2019; Yang et al., 2023a; Zheng and Yi, 2025) to capture this electromagnetic-
 10 induced softening effect.

$$11 \quad \tau_c^\alpha(J) = \frac{\tau_c^\alpha}{(1 + \frac{J^2}{J_0^2})} \quad (7)$$

12 where J is the applied current density and J_0 is the reference current density to be fitted depending on
 13 the materials used. Since previous studies on copper have reported no observable change in the elastic
 14 modulus during the elastic deformation stage (Xu et al., 2022; Zhang et al., 2018), the influence of current
 15 density on μ is considered negligible. So, the expressions for g^α and ΔG_0^α can be derived:

$$16 \quad g^\alpha(J) = \frac{g^\alpha}{(1 + \frac{J^2}{J_0^2})} \quad (8a)$$

$$17 \quad \Delta G_0^\alpha(J) = \frac{\Delta G_0^\alpha}{(1 + \frac{J^2}{J_0^2})} \quad (8b)$$

18 The essence of this change lies in the electromagnetic field during EAD, which results in electron spin
 19 states change (Molotskii and Fleurov, 1997b) at dislocation core and alters the effective depinning energy
 20 (Lahiri et al., 2019; Molotskii and Fleurov, 1997a, b; Molotskii et al., 1995; Yang et al., 2023a). The
 21 reduction of the depinning barrier upon the electromagnetic field has been confirmed by experiments in
 22 broad temperature range (Jemielniak and Krolkowski, 1985; Molotskii and Fleurov, 1997a; Molotskii,
 23 2000; Molotskii et al., 1995). Thus, the dislocation motions are tended to be facilitated by the
 24 electromagnetic field during EAD. However, for non-continuous pulsed DC, the surrounding magnetic
 25 field resembles that of an AC excitation due to its time-varying nature. Under such conditions, the skin
 26 effect proved to be negligible. The skin depth is calculated as (Hayt Jr, 1989):

$$27 \quad \delta_m = \sqrt{\frac{2\rho_e}{2\pi f \mu_{copper}}} \quad (9)$$

28 where ρ_e is the electrical resistivity (Lu et al., 2004) ($1.68 \times 10^{-8} \Omega \cdot m$), f is the frequency of current
 29 in this study (2.5Hz) and μ_{copper} is the magnetic permeability of copper ($1.26 \times 10^{-6} \text{H} \cdot m^{-1}$). The
 30 numerical calculation yields a skin depth of 41.26 mm, significantly greater than half of the sample
 31 thickness (0.5 mm). In this scenario, the homogenization method is applicable and the skin effect is

1 ignored in this study.

2 3.3. The dislocation evolution mechanisms influenced by electricity

3 In this section, the superscript α is omitted from all equations and expressions in this subsection
4 where applicable. The influence of electric current on dislocation evolution is discussed here. For clarity
5 and coherence, the analysis is limited to a single slip system. The dislocation evolution is considered by
6 a modified Kocks-Mecking relationship. The evolution of dislocations in the proposed model is governed
7 by mechanisms including multiplication and dynamic recovery (Austin and McDowell, 2011; Beyerlein
8 and Tomé, 2008; Bong et al., 2019). The influence of electricity is incorporated inside by considering the
9 current density as a state variable for several physical parameters. The dislocation density evolution law
10 is expressed as (Sun et al., 2024):

$$11 \quad \frac{d\rho}{d\gamma} = \frac{d\rho_{mul}}{d\gamma} - \frac{d\rho_{ann}}{d\gamma} \quad (10a)$$

$$12 \quad \frac{d\rho_{mul}}{d\gamma} = \frac{k_{\rho,mul}}{\bar{L}} \quad (10b)$$

$$13 \quad \frac{d\rho_{ann}}{d\gamma} = \left(\frac{d\rho_{mul}}{d\gamma} \right) \left[\frac{c_h b}{g} \left(1 - \frac{kT}{Db^3} \log \frac{|\dot{\epsilon}|}{\dot{\epsilon}_0} \right) \right]^2 \rho \quad (10c)$$

14 In this form, $k_{\rho,mul}$ controls the multiplication rate of the dislocation, $\bar{L} = 1/\sqrt{\sum_{\alpha} \rho_{\alpha}}$ represents
15 the length of the mean free path of dislocation movements depending on the total dislocation density
16 ($\rho_{tot} = \sum_{\alpha} \rho_{\alpha}$) (Beyerlein and Tomé, 2008; Stricker and Weygand, 2015; Sun et al., 2024; Zecevic et
17 al., 2018) and c_h is a coefficient controlling the dislocation hardening (Sun et al., 2024). $|\dot{\epsilon}|$ and $\dot{\epsilon}_0$
18 are equivalent strain rate and the reference strain rate, respectively. Combining the three equations above
19 yields the following result:

$$20 \quad \frac{d\rho}{d\gamma} = \frac{k_{\rho,mul}}{\bar{L}} - \left(\frac{k_{\rho,mul}}{\bar{L}} \right) \left[\frac{c_h b}{g} \left(1 - \frac{kT}{Db^3} \log \frac{|\dot{\epsilon}|}{\dot{\epsilon}_0} \right) \right]^2 \rho \quad (10d)$$

21 Here, g essentially acts as a constant governing dislocation recovery. Letting Eq. (10d) to zero, the
22 saturation dislocation density in this relation is determined by g . A smaller value of g implies a lower
23 energy requirement for dislocation recovery, thereby resulting in a reduced saturation dislocation density.

24 Prior research suggests that the mean free path of dislocations in copper can be altered through the
25 electromagnetism induction process, as presented by post-experiment measurements and simulation
26 works (Alshits et al., 1997; Molotskii et al., 1995; Xu et al., 2022; Yang et al., 2023a). The change of the
27 mean free path in copper with and without an electric current could be described by the following
28 quadratic relationship:

$$29 \quad \bar{L}(J) = \bar{L}(0) \left(1 + \frac{J^2}{J_0^2} \right) \quad (11a)$$

30 where J_0 is the same reference current density as in the previous section. In several models (Molotskii
31 et al., 1995; Xu et al., 2022; Yang et al., 2023a), \bar{L} is treated as a state constant. However, in reality, \bar{L}
32 evolves with dislocation evolution (Beyerlein and Tomé, 2008; Sun et al., 2024; Zecevic et al., 2018). In
33 this study, we propose that the influence of electric current on \bar{L} essentially arises from the effect of
34 electromagnetic field energy on the dislocation dynamic processes. The larger \bar{L} implies lower final
35 dislocation density and decreased multiplication process. In this study, this is presented as a decrease in

1 the dislocation multiplication rate, which can be expressed in the following form:

$$2 \quad \left. \frac{d\rho_{mul}}{dy} \right|_{(J)} = \frac{\left. \frac{d\rho_{mul}}{dy} \right|_{J=0}}{\left(1 + \frac{J^2}{J_0^2}\right)} \quad (11b)$$

3 which is:

$$4 \quad \left(\frac{k_{\rho,mul}}{\bar{L}} \right) \Big|_{(J)} = \frac{k_{\rho,mul}}{\bar{L} \left(1 + \frac{J^2}{J_0^2}\right)} \quad (11c)$$

5 For more convenient implementation in simulations, the following form is adopted in this study:

$$6 \quad k_{\rho,mul}(J) = \frac{k_{\rho,mul}}{\left(1 + \frac{J^2}{J_0^2}\right)} \quad (11d)$$

7 Eq. (11d) implies that the presence of electric current reduces the probability of new dislocation
8 generation through dislocation multiplication during dislocation dynamic evolution.

9 Furthermore, the electric current-induced reduction in dislocation core energy decreases the
10 annihilation barrier by introducing electrostatic forces (Sutton and Todorov, 2021) and energy transfer
11 (Xu et al., 2023) into the dislocation core region. The dynamic dislocation recovery tends to be facilitated
12 during plastic deformation (Ao et al., 2018; Dai et al., 2024; Tiwari et al., 2022; Xiang and Zhang, 2019;
13 Xu et al., 2023; Zhao et al., 2019). In this work, a recently adopted quadratic decay form is used to
14 describe the energy attenuation associated with electric current. This choice is directly supported by the
15 De Broglie theory and has been applied in previous studies (Dai et al., 2024; Li et al., 2013; Xu et al.,
16 2023). The linear decay form derived from classical transport theory has been shown in earlier works to
17 be insufficient in magnitude ($\lesssim 10^{-2}$ MPa) (Li et al., 2022b; Sprecher et al., 1986) to account for the
18 observed electroplastic effects, and is therefore not considered in the present model. Taking into account
19 the effects already considered in Section 3.2, the expression for $g(J)$ under the combined influence of
20 electromagnetic conditions is given as Eq. (12a):

$$21 \quad g(J) = \frac{g - \Delta e}{\left(1 + \frac{J^2}{J_0^2}\right)} = \frac{g - KJ^2}{\left(1 + \frac{J^2}{J_0^2}\right)} \\ = \frac{g \times \left(1 - \frac{J^2}{\frac{g}{K}}\right)}{\left(1 + \frac{J^2}{J_0^2}\right)} \quad (12a)$$

22 The term $\Delta e = KJ^2$ is a normalized statistical energy transfer due to electron-dislocation scattering
23 (Dai et al., 2024; Li et al., 2013; Xu et al., 2023) and $\sqrt{g/K}$ has the dimension of current density.
24 However, since $g(J)$ is a dimensionless parameter representing a statistical energy barrier and a factor
25 of ΔG_0^α , we impose two assumptions: (1) $g(J) \geq 0$ at ambient temperature for all $J > 0$, consistent
26 with its interpretation as energy barrier; (2) $\lim_{J \rightarrow +\infty} g(J) = 0$, that the barrier vanishes to zero at extremely
27 high current densities. Thus, this modification on $g(J)$ not only regularizes the function mathematically
28 but also preserves its physical interpretation. So, to prevent unphysical values, the following form is
29 adopted (12b):

$$\begin{aligned}
g(J) &\cong \frac{g \times \left(1 + \frac{J^2}{\frac{g}{K}}\right)^{-1}}{\left(1 + \frac{J^2}{J_0^2}\right)} \\
&= g \times \left[1 + \frac{J^2}{J_0^2} + \left(\frac{J^2}{\frac{g}{K}}\right) + \left(\frac{J^2}{J_0^2}\right) \cdot \left(\frac{J^2}{\frac{g}{K}}\right)\right]^{-1} \\
&= g \times \left[1 + \frac{J^2}{J_1^2} + \left(\frac{J^2}{J_0^2} \cdot \frac{J^2}{\frac{g}{K}}\right)\right]^{-1} \tag{12b}
\end{aligned}$$

This form captures the energy attenuation behavior proposed by (Gao et al., 2022) at large current densities, but the Gao model diverges near $J = 0$. Conversely, the classical quadratic decay associated with electron scattering approximates the behavior near $J = 0$, but diverges to negative values at very high currents. Both of these limits are physically unreasonable. In contrast, the present form satisfies the required properties at both $J = 0$ and $J \rightarrow +\infty$, maintains monotonic decay, and ensures that $g(J)$ remains non-negative, thereby preserving both mathematical consistency and physical plausibility. The descriptions in detail on this modelling are presented in Supplementary Materials Part 6.

In Eq. (12b), $J_1 = \sqrt{\frac{g}{K} \cdot J_0^2 / \left(J_0^2 + \frac{g}{K}\right)} < J_0$ is a reduced parameter to be fitted with the dimension of the current density. Notably, the parameter J_0 has been experimentally measured and fitted in previous studies (Dai et al., 2024; Li et al., 2013) to be on the order of $\sim 10^3$ A/mm², and a similar magnitude will be observed in the present work. Under this magnitude, J^2/J_0^2 is estimated to be $\sim 10^{-2}$ in this study, thus the second-order term in Eq. (12b) is ignored in front of $J^2/\left(\frac{g}{K}\right)$ and the equation could be simplified as:

$$g(J) \cong g \times \frac{1}{\left(1 + \frac{J^2}{J_1^2}\right)}, \quad \text{with } (J_1 < J_0) \tag{12c}$$

The form of Eq. (12c) is a simplified form to be considered in simulations and J_1 is the only electric-related parameter to be fitted, thus reducing the complexity of the model. This simplification is based on the real current density in this study, also applicable to other (Xu et al., 2022; Zhang et al., 2018) EAD scenarios with similar current density. This formulation closely resembles the mathematical form presented in Section 3.2, thereby facilitating more convenient mathematical processing. Finally, the dislocation density evolution law is presented as:

$$\frac{d\rho}{d\gamma} = \frac{k_{\rho,mul}}{\bar{L} \cdot \left(1 + \frac{J^2}{J_0^2}\right)} - \left(\frac{k_{\rho,mul}}{\bar{L} \cdot \left(1 + \frac{J^2}{J_0^2}\right)} \right) \left[\frac{c_h b}{g} \left(1 + \frac{J^2}{J_1^2}\right) \left(1 - \frac{kT}{Db^3} \log \frac{|\dot{\epsilon}|}{\dot{\epsilon}_0}\right) \right]^2 \rho \tag{13}$$

This modified constitutive law incorporates the influence of electric current during EAD tests by introducing electric current-dependent terms into the dislocation evolution framework. As a result, it effectively captures the profile of work-hardening behavior induced by EAD, allowing also for accurate simulations of local strain–stress responses, verifying the validity of Eq. (13) (in Section 4.2).

27

28 3.4. The dislocation interaction and the grain boundary effect

1 The electricity-induced dislocation activities will lead to a change in the slip resistance, thereby
 2 influencing the overall mechanical behaviors of polycrystalline materials. This dislocation hardening rule
 3 is based on line tension theory (Kocks, 1966) and dislocation interaction principle (Bassani and Wu,
 4 1991; Wu et al., 1991), expressed as:

$$5 \quad \tau_b = c_h \mu b \sqrt{\sum_{\beta}^N h^{\alpha\beta} \rho_{\beta}} \quad (14)$$

6 where $h^{\alpha\beta}$ is the latent hardening coefficient matrix, capturing the contributions of different dislocation
 7 interaction modes across slip systems (Bassani and Wu, 1991; Cuitino and Ortiz, 1993; Franciosi et al.,
 8 1980) and c_h is the Taylor relation parameter to be fitted (Sun et al., 2024; Taylor, 1934), same as the
 9 one in Eq. (15). For the twelve $\langle 110 \rangle \{111\}$ slip systems in FCC system, five interaction modes between
 10 slip systems are defined as no junction (NJ), Hirth lock (HL), coplanar junction (CJ), glissile junction
 11 (GJ), and sessile junction (SJ), determined by the Frank rule, the directional alignment of Burgers vectors,
 12 and their coplanarity. The values of the corresponding latent hardening coefficients, denoted as h_{NJ} ,
 13 h_{HL} , h_{CJ} , h_{GJ} and h_{SJ} , follow the following monotone order.

$$14 \quad h_{NJ} < h_{HL} < h_{CJ} < h_{GJ} < h_{SJ} \quad (15)$$

15 and the coefficient for the self-interaction, $h_{NJ} = h^{\alpha\alpha}$, set to 1. Previous studies (Akhondzadeh et al.,
 16 2020; Gérard et al., 2013) have pointed out that, in complex loading polycrystalline cases, the optimal
 17 latent hardening coefficients may differ from those derived from single-crystal experiments. Therefore,
 18 in the present work, these constants are treated as fitting parameters, with reference values taken from
 19 prior literature (Cuitino and Ortiz, 1993).

20 Grain boundaries will also hinder the dislocation movement and affect the slip resistance; therefore,
 21 they are considered in the polycrystalline copper system. Two key mechanisms are considered: the Hall-
 22 Petch effect and dislocation accumulation at grain boundaries. The Hall-Petch effect (Hall, 1951; Petch,
 23 1953) quantifies the resistance to dislocation motion as inversely proportional to the square root of the
 24 grain size \bar{D} . This relationship has been implemented in some VPSC-Type codes (Zhu et al., 2021).

$$25 \quad \tau_{GB} = k_{slip} \sqrt{1/\bar{D}} \quad (16)$$

26 Here, k_{slip} is a material constant calculated by the method in (Zhu et al., 2021). The average grain size
 27 \bar{D} is calculated based on the EBSD results of undeformed area, approximately 24 μm (Fig. 5). To
 28 different samples, tiny changes of \bar{D} are applied due to slightly different grain sizes (Fig. 5). τ_{GB} is
 29 treated as constant in the present study.

30 The dislocation accumulation at grain boundaries is modeled as:

$$31 \quad \frac{d\rho_{acc}}{d\gamma} = k_{acc} \frac{d\rho_{ann}}{d\gamma} \quad (17)$$

32 where k_{acc} is the characteristic proportion for dislocation density accumulations and is fitted here
 33 (Beyerlein and Tomé, 2008), and ρ_{ann} is the dislocation annihilation term. The overall slip resistance,
 34 considering the contribution of dislocation interaction, Hall-Petch effect and the forest hardening, is

1 finally determined as:

$$2 \quad \tau_f = \tau_b + \tau_{GB} + c_h Gb \sqrt{\rho_{acc}} \quad (18)$$

3 **3.5. The configurations of the theoretical simulation**

4 In this work, 800 differently oriented grains are configured to form the initial texture of the Cu
5 polycrystalline system, derived from EBSD results and processed using MTEX in MATLAB. The
6 boundary conditions are maintained constant throughout the simulation, ensuring full consistency across
7 all incremental timesteps during the calibration process. A uniaxial tensile strain rate of $5 \times 10^{-3} \text{ s}^{-1}$ is
8 applied to replicate the experimental setup, with a strain step increment as 6.5×10^{-6} for 4×10^4 steps in
9 total. Thus, the numerical time integration step is on $\sim 1\text{ms}$ scale. The different current density profiles
10 (Fig. 4) are implemented, while the experimentally observed millisecond-scale variations in
11 synchronous pulsing current time phases (Δt) are also incorporated into the simulations to enhance
12 subsequent comparison with real data. The present simulations incorporated not only information from
13 monocrystals to polycrystals but also achieved temporal precision ranging from milliseconds to minutes
14 scale.

15 **4. Results and discussions**

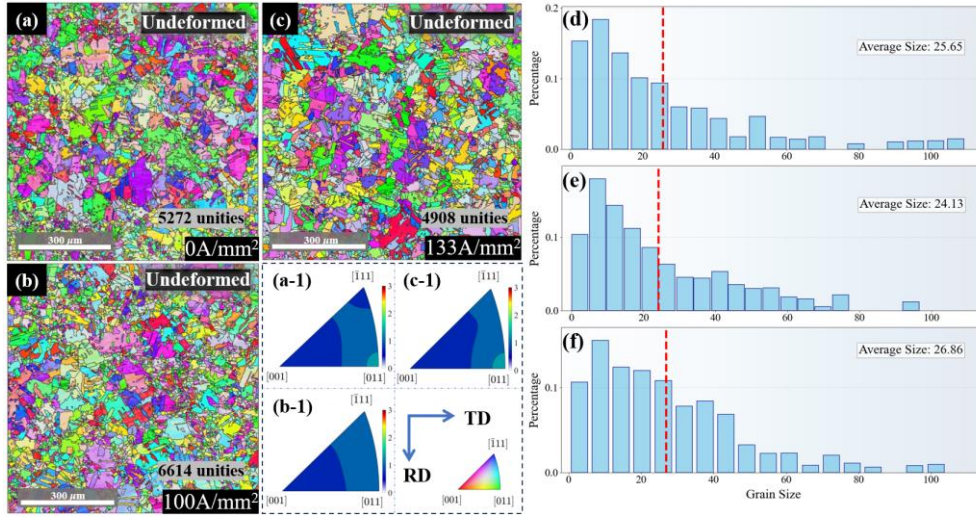
16 In this Section, we first analyze the mechanical responses and microstructural characterization to
17 provide an overall understanding of the EAD deformation behavior. The crystal plasticity model is then
18 calibrated and validated against the experiments. Section 4.3 examines the simulated evolution of GNDs
19 and SSDs to clarify the dislocation origin of the EAD-induced softening, while Section 4.4, by EC-
20 EVPSC simulations, disentangles the two-stage local stress fluctuations by artificially isolating current
21 effects in the Orowan equation and the dislocation evolution law. Finally, Section 4.5 discusses the
22 physical implications of the proposed mechanism and systematically compares our study with existing
23 ones.

24 **4.1. Experimental results and analysis**

25 This section reports tensile test results, material characterizations and corresponding analysis. First,
26 the number of grains within the EBSD field of view for undeformed samples at 0, 100 and 133 A/mm² is
27 shown in Fig. 6 (5272, 6614 and 4908 grains, respectively). Inverse pole figures (IPFs) along the rolling
28 direction reveal similarly weak textures, while pole figures (PFs) in Fig. S2 (in Supplementary
29 Materials) display a slight remnant of the typical rolling texture, confirming identical initial textures.
30 Grain size histograms show comparable values (25.65 μm , 24.13 μm and 26.86 μm), ensuring
31 consistency of undeformed microstructures across different loadings.

32 The tensile test results are presented in Fig. 7. Fig. 7(a) shows engineering stress–strain curves for
33 samples deformed under 0, 100, and 133 A/mm². All specimens reached a maximum engineering strain
34 of 0.3 (~ 0.262 true strain) without fracture. Slight differences in yield stress arise from minor variations
35 in grain size and initial dislocation density, not from the applied pulse. At $\varepsilon_{true} < 0.002$, the given strain
36 rate and pulse frequency allow at most one pulse, and its energy is insufficient to activate a large amount
37 of local dislocation recovery. Maximum stresses decreased monotonically with current density, with
38 325, 285, and 266 MPa for 0, 100, and 133 A/mm², respectively. The 40 MPa reduction between the
pure mechanical and 100 A/mm² cases exceeds that expected from the temperature-controlled condition
in

1 this study, demonstrating a significant electroplastic effect in pure copper. Justifications to neglect local
 2 thermal effects are in Supplementary Materials Part 5.



3
 4 **Fig. 6** (a–c) EBSD micrographs of undeformed regions in specimens with current densities of 0, 100,
 5 and 133 A/mm², with corresponding inverse pole figures along RD in (a-1), (b-1), and (c-1), showing
 6 random crystallographic orientations. (d–f) Grain size histograms from (a–c) reveal comparable
 7 distributions and mean values.

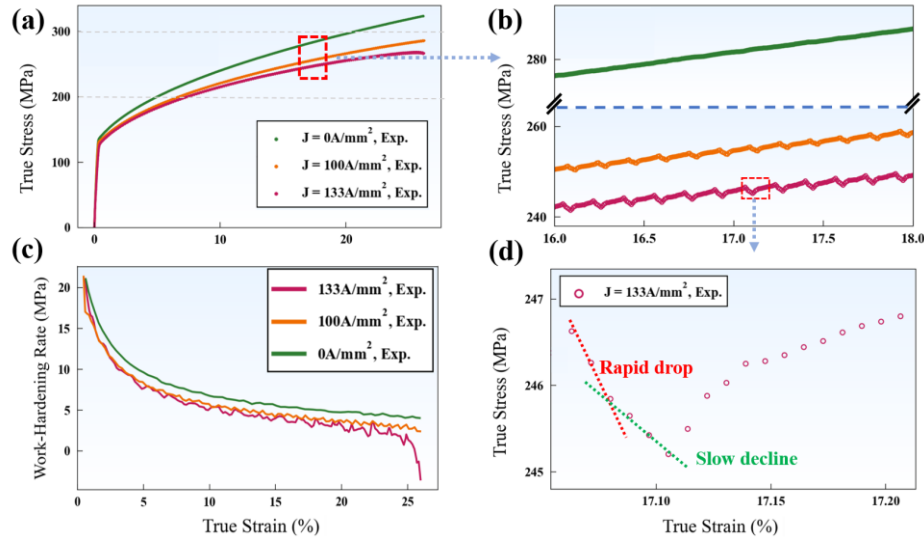
8 Fig. 7 (b) highlights fluctuations in the stress responses: the pure mechanical curve is smooth, whereas
 9 100 and 133 A/mm² curves show periodic variations, increasing in amplitude with current. Fig. 7 (d)
 10 details the stress response within a single period of electric pulse with the 133 A/mm² electric density,
 11 revealing a characteristic “rapid-slow transition” drop: an initial “rapid drop” within ~35 ms of current
 12 application, followed by a “slow decline”, and subsequent rebound with hardening after current removal.
 13 This behavior, representative of all mechanical response curves, aligns with some reported simulation
 14 profiles under one-pulse electric shocking (“instantaneous drop–slow decline”) (Dai et al., 2024; Niu et
 15 al., 2025; Yan et al., 2023). Under well-controlled temperatures and negligible local heating (see in
 16 Supplementary Materials Part 5), the “slow decline” in stress is interpreted as possible accelerated
 17 dislocation dynamic recovery induced by electricity (Dai et al., 2024; Tiwari et al., 2022), influencing
 18 overall work-hardening rate ($\theta = d\sigma/d\varepsilon$). These observations provide the first detailed experimental
 19 observation of individual small stress drops in copper under pulsed EAD.

20 Fig. 7 (c) presents the overall work-hardening rate to show a decreasing trend with increasing current
 21 density. **Fig. 7 (c) corresponds to the overall work-hardening of curves in Fig. 7(a).** This work-hardening
 22 rate is deduced from the envelopes of the fluctuated stress curves, extracted using a Savitzky-Golay filter
 23 (Savitzky and Golay, 1964) to smooth out the small fluctuations. The overall work-hardening rate reveals
 24 the reduction induced by the current is consistently observed throughout the entire large deformation
 25 process. At each strain point in Fig. 7 (c), the relation that $\theta_{J=133A/mm^2}(\varepsilon) < \theta_{J=100A/mm^2}(\varepsilon) <$
 26 $\theta_{J=0A/mm^2}(\varepsilon)$ holds, this denotes the dislocation density accumulations may have been reduced
 27 throughout the deformation.

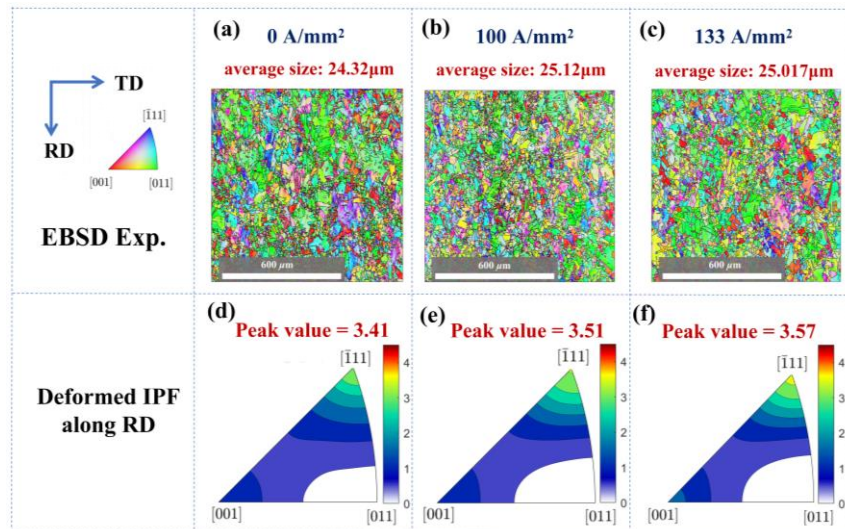
28 Large-area EBSD was used to check if the applied pulse may have an apparent influence on the
 29 deformation mechanism and alter the deformed texture. The EBSD samples are selected in the deformed
 30 area (Fig. 2) from the tensile samples after deformation under the current density of 0, 100, and
 31 133 A/mm². The large scan area (1×1 mm²) ensures the texture data is statistically representative. Fig. 8

1 shows the deformed EBSD maps and IPFs along //RD, with grains elongated along RD and no significant
 2 change in size or grain morphology compared to the results of normal mechanical tests (Wang et al.,
 3 2022). IPFs reveal $\langle 111 \rangle$ //RD peaks typical of polycrystalline copper. Across all current densities, the
 4 $\langle 111 \rangle$ //RD component remains nearly stable, with only slight increases likely due to sample selection.
 5 The $\langle 111 \rangle$ //RD pole intensity is not much influenced by EAD process.

6 Due to recent debates on the activation of non-octahedral slips during EAD (Li et al., 2016; Xu et al.,
 7 2022; Xu et al., 2023), further two-beam TEM characterizations have been implemented to determine
 8 dominant ones. TEM shows no abnormal $\{100\}$ -plane systems activation and such systems are excluded
 9 from subsequent simulations. The experimental details are in Supplementary Materials Part 7.



10
 11 **Fig. 7** Stress responses of samples under different pulsed current intensities. (a) Stress–strain curves at
 12 0, 100, and 133 A/mm². (b) Enlarged view showing local fluctuations induced by electricity. (c)
 13 Hardening rates under different currents, showing reduced accumulated hardening. (d) Fast and slow
 14 drops in stress under pulsing.



15
 16 **Fig. 8** (a–c) EBSD maps of the deformed areas under different pulsed current intensities. (d–f) IPF
 17 maps along the RD axis, derived from the EBSD measurements, showing a quasi-stable intensity.

18 **4.2. Calibration and verification of the self-consistent model**

1 This section presents the calibration and validation of the EC-EVPSC model. Non-electric parameters
2 were fitted using literature data and the stress-strain curve at the electric density $J = 0 \text{ A/mm}^2$, while
3 current-related parameters (J_0 and J_1) were determined from the stress response at $J = 100 \text{ A/mm}^2$. The
4 stress curve at $J = 133 \text{ A/mm}^2$ was then simulated. Quantitative simulations demonstrate the model's
5 ability to reproduce strain-stress responses and deformed textures under different conditions. The
6 quantitative analysis on dislocation density will be demonstrated in Section 4.3.

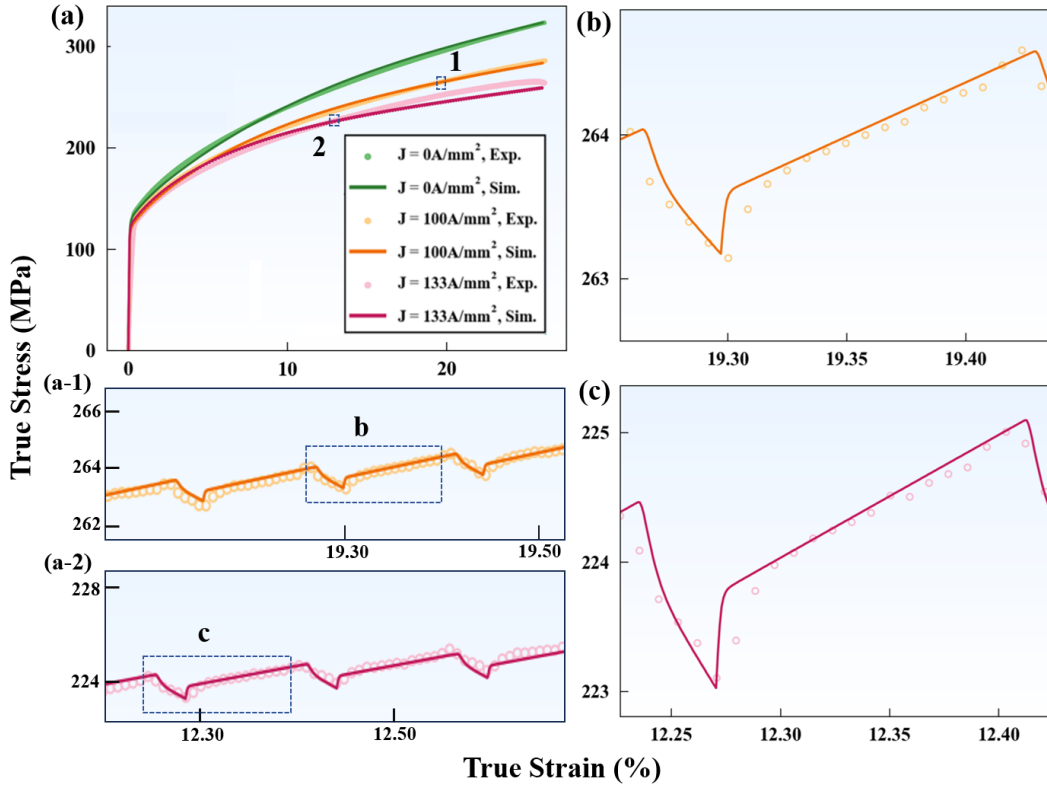
7 The parameters for purely mechanical crystal plasticity simulations are listed in Table 2. Classical
8 physical constants, such as the elastic stiffness constant (C_{ij}), shear modulus (μ), and Burgers vector
9 length (b^α) are directly taken from the literature. Other parameters, including v_0 , g^α , D^α , τ_c , $h^{\alpha\beta}$,
10 $k_{\rho,mul}$, c_h and $\dot{\epsilon}_0$ were referenced from previous studies and adjusted for the specific case under
11 consideration. Initial dislocation density on each slip plane (ρ_0^α) and grain-size induced resistance are
12 calibrated systematically to achieve agreement with the measured yield stress. The initial dislocation
13 density and the characteristic proportion for dislocation accumulations (k_{acc}) are aligned with the same
14 order of magnitudes as shown in prior research (Beyerlein and Tomé, 2008; Lei et al., 2025). The
15 parameters obtained following the above procedure are listed in Table 2 below. The slip system
16 considered in this study is the traditional $\langle 110 \rangle \{111\}$ system. Unless otherwise specified, these
17 parameters remain unchanged in subsequent simulations. As shown by the green lines in Fig. 9 (a), the
18 simulated stress-strain curves compare well with pure mechanical experimental data.

19 **Table 2** The model parameters used in CP model.

| Parameters | Value and unity | Reference |
|--|---|-------------------------------------|
| C_{11}, C_{12}, C_{44} | 168.4, 121.4, 75.4 GPa | (Freudenberger and Warlimont, 2018) |
| μ | 46 GPa | (Freudenberger and Warlimont, 2018) |
| b^α | $2.56 \times 10^{-10} \text{ m}$ | (Freudenberger and Warlimont, 2018) |
| g^α | 5×10^{-3} | *(Beyerlein and Tomé, 2008) |
| D^α | 370 MPa | *(Beyerlein and Tomé, 2008) |
| ΔG^α | 1.05 eV | (Hull and Bacon, 2011) |
| τ_c | 7 MPa | (Lahiri et al., 2019) |
| $h_{NJ}, h_{HL}, h_{CJ}, h_{GJ}, h_{SJ}$ | 1.0, 3.0, 5.0, 5.0, 9.0 | *(Cuitino and Ortiz, 1993) |
| $k_{\rho,mul}$ | $1.2 \times 10^8 \text{ m}^{-1}$ | (Beyerlein and Tomé, 2008) |
| v_0 | $2 \times 10^2 \text{ m} \cdot \text{s}^{-1}$ | *(Sun et al., 2024) |
| c_h | 0.097 | (Fitted) |
| $\dot{\epsilon}_0$ | $1 \times 10^7 \text{ s}^{-1}$ | (Beyerlein and Tomé, 2008) |
| ρ_0^α | $4.25 \times 10^{12} \text{ m}^{-2}$ | (Lei et al., 2025) |

| | | |
|-------------|--------|--|
| τ_{GB} | 28 MPa | *(Ghassemali et al., 2015; Zhu et al., 2021) |
| k_{acc} | 0.05 | *(Beyerlein and Tomé, 2008) |

1 * This symbol means we only used qualitative relations or calculation methods in these references to
2 fit parameters.



3 **Fig. 9** (a) Experimental (Exp.) and simulated (Sim.) stress-strain curves under various pulsed
4 currents, with two regions (1 and 2) at 100 A/mm² and 133 A/mm² are highlighted. (a-1, a-2)
5 Magnified views of Region 1 and 2 in (a). (b-c) Magnified views of regions **b** and **c**, showing
6 detailed stress responses accurately captured by the EC-EVPSC model.
7

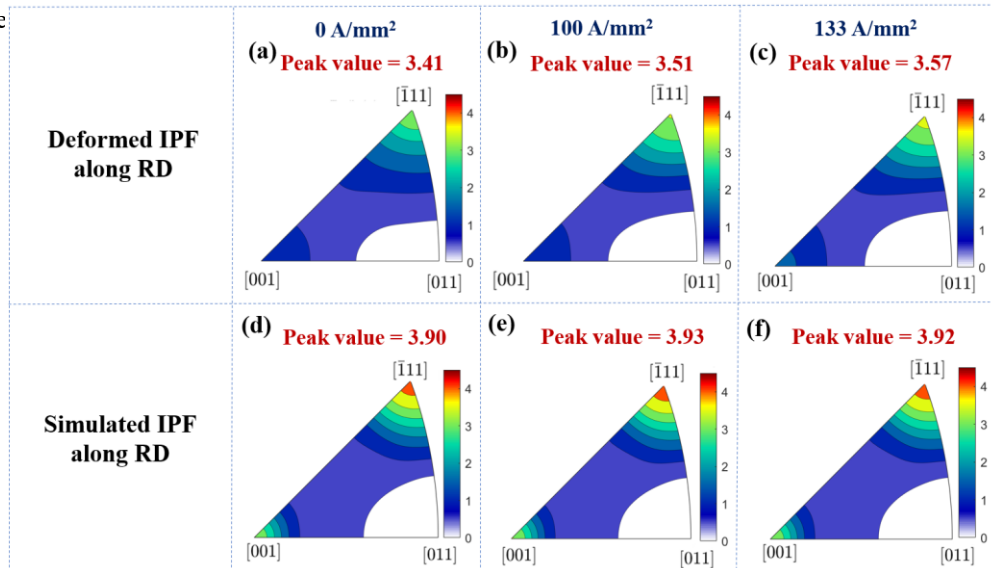
8 The model calibration and validation were performed in two steps. First, the electric parameters (J_0
9 and J_1) were determined by fitting the experimental data at $J = 100$ A/mm². Guided by previous
10 research (Lahiri et al., 2019; Yang et al., 2023a), J_0 is associated with the rapid stress drop. Therefore, it
11 was calibrated against this rapid drop stage. Subsequently, the slow dynamic decline was captured by
12 adjusting J_1 , as this parameter governs the dynamic dislocation recovery in our model (Eq. (13)).
13 Consequently, the entire fitting procedure for a given current density requires information from only a
14 single stress drop event. Further investigation into the deformation mechanisms dominated by these
15 parameters and new insights will be provided in Sections 4.3 and 4.4.

16 The goal has been to capture both the macroscopic hardening behavior and the local stress
17 fluctuations (as shown in Fig. 9 (a)). To synchronize the simulated pulse phase with the experimental
18 data, a time phase difference introduced by the experiment system of $\Delta t = +5.5$ ms was applied. This
19 synchronization has been validated by the results in Fig. 9 (a-1). Additionally, the initial dislocation
20 density ρ_0 was slightly adjusted to $3.9 \times 10^{12} \text{m}^{-2}$ to account for minor variations in the experimental
21 yield stress. The difference of the yield stresses (~ 5 MPa) falls within the typical uncertainty observed

1 for different samples of the same material (Niu et al., 2025). Upon calibration, the optimized parameters
 2 were determined as $J_0 = 700\text{A/mm}^2$ and $J_1 = 85\text{A/mm}^2$. Fig 10. (b) (the magnified area from Fig. 9 (a))
 3 demonstrates that the calibrated model accurately reproduces the detailed stress responses within a
 4 single pulse period.

5 Subsequently, to validate the predictive capability of the model, these calibrated parameters were
 6 applied to the $J = 133\text{A/mm}^2$ case. All material and electric parameters were held constant, with only
 7 the time phase difference adjusted to $\Delta t = -9.0\text{ms}$ according to our experiment record to match the
 8 experimental phase. As shown in Fig. 9 (a) and (c), the simulation results show excellent agreement
 9 with the experimental curve for this higher current density, successfully predicting both the overall
 10 stress-strain response and the detailed fluctuation characteristics.

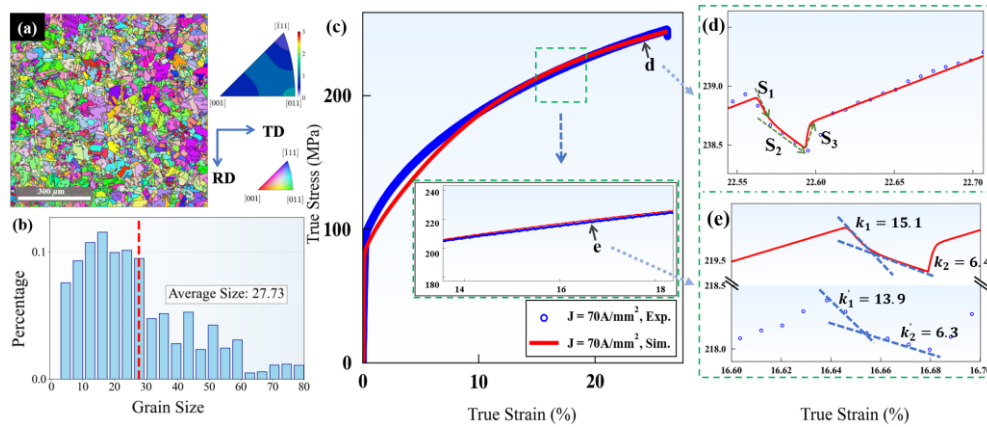
11 This study marks the first example in which a crystal plasticity model accurately reproduces the local
 12 stress-strain response induced by the EAD process. The results offer preliminary validation of the
 13 model mechanisms and further highlight the EVPSC framework's capability to predict local stress
 14 responses upon changes in loading conditions (Wang et al., 2016; Wang et al., 2010). Fig. 10
 15 demonstrates direct comparisons of the RD-direction IPFs of final textures between the experimental
 16 results and simulation results, which also shows consistency. Notably, the $\langle 111 \rangle // \text{RD}$ intensity
 17 remains stable across simulations at different current densities, consistent with experimental
 18 observations (see Section 4.3 for further discussion). Although the modeling reproduces the
 19 experimental trend quantitatively, it tends to overpredict texture intensity, a well-documented limitation
 20 of VPSC-type models (Agnew et al., 2005; Gouriet et al., 2015; Kang et al., 2022). This originates from
 21 the classical self-consistent assumption that each grain interacts with a homogeneous effective
 22 medium (HEM), causing grains with similar orientations to develop nearly identical plastic
 23 responses and texture evolution, whereas in reality each grain is embedded in a heterogeneous
 24 microstructural environment where differences in neighboring orientations, morphologies, and
 25 constraint conditions play a decisive role in governing its rotation. Thus, the texture intensity may be
 overpre



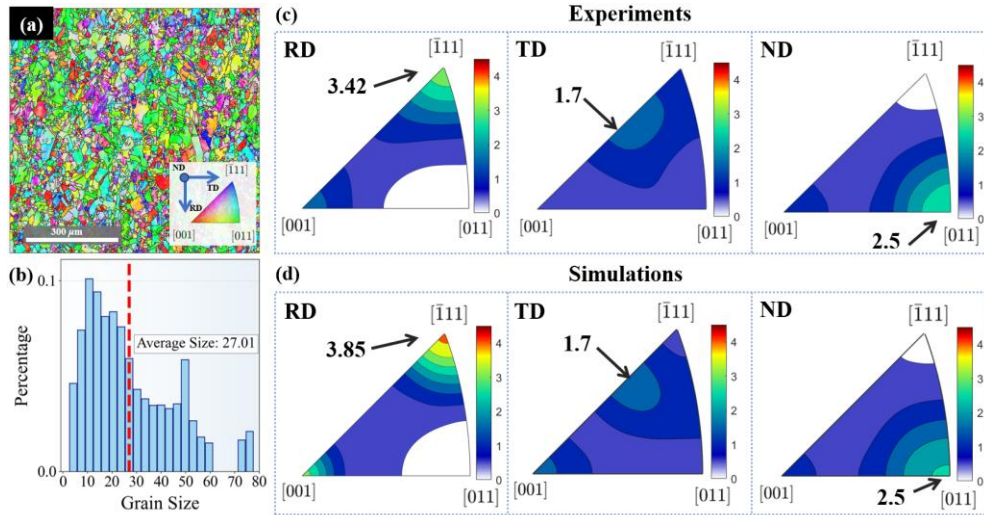
26
 27 **Fig. 10** (a-c) IPF maps along the RD axis, derived from the EBSD measurements. (d-f) Simulated
 28 IPF distributions using the EC-SC model, indicating agreement with the experimental observations
 29 where the $\langle 111 \rangle // \text{RD}$ pole intensity increased significantly after tensile tests, demonstrating a
 30 typical FCC metal's texture after tensile tests.

1 To further validate the model's effectiveness, a separate case ($J = 70 \text{ A/mm}^2$) with a distinct initial
 2 grain size ($\sim 27 \mu\text{m}$) and dislocation density ($0.8 \times 10^{12}/\text{m}^2$ per slip) was used for verification. The large-
 3 area EBSD map, initial IPF along the RD direction (showing weak texture), and initial grain size
 4 distribution are provided in Fig. 11 (a-b). All parameters remained unchanged except for the initial
 5 dislocation density and the grain-size-related slip resistance to match the initial state of this distinct
 6 sample. Fig. 11 (c) shows excellent agreement between the simulated stress curve and the experimental
 7 data. Details of the arrow-marked regions are illustrated in Fig. 11 (d-e): Fig. 11 (d) demonstrates the
 8 model's consistent accuracy in capturing fine stress fluctuations, while Fig. 11 (e) shows results in
 9 another non-overlapping region. Notably, even in this region the model reproduces nearly identical
 10 fluctuation features and local slopes, differing only by an $\approx 2 \text{ MPa}$ offset. In Fig. 11(e), the values of local
 11 slopes have been indicated inside, obtained by linear regression. k_1 and k'_1 correspond to the “rapid
 12 drop” stage while k_2 and k'_2 correspond to the “slow decline” one. All these predictive features can
 13 validate this model's capability in describing the EAD processes, both in the local fluctuations and the
 14 overall hardening features.

15 Moreover, Fig. 12 presents the IPFs for the validation case, displaying results along RD, TD, and ND.
 16 While the RD direction exhibits a consistent pattern with previous findings, the TD and ND directions
 17 show excellent agreement with experimental data. In addition, the grain size has not been changed after
 18 EAD, consistent with the observation and analysis in Section 4.1. These results furtherly validate that the
 19 model effectively captures the texture evolution of copper during the EAD process. An additional
 20 validation case under current density



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 22 **Fig. 11** (a-b) EBSD grain image of the undeformed sample and initial grain size distribution before
 23 deformation. (c) Experimental (Exp.) and Simulated (Sim.) stress–strain curves under a pulsed
 24 current density of 70 A/mm^2 and an initial dislocation density of $0.8 \times 10^{12}/\text{m}^2$ in each slip system,
 25 validating the accuracy of the calibrated model. (d) Magnified view of the stress–strain response
 26 during several electric pulses. (e) Quantitative agreement of the stress evolution during the rapid
 27 drop, slow drop, and post-current lift stages within a single pulse.



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2 **Fig. 12** (a) EBSD grain image of the deformed sample. (b) Grain size distribution, showing
3 minimal change from the undeformed region. (c-d) Experimental and simulated IPFs along RD,
4 TD, and ND; arrows indicate peak pole intensities. Qualitative comparison shows the model
5 reproduces the deformed texture well.

6 In Appendix 5, we present a further validation conducted under operating parameters of a 10% duty
7 cycle, 1 Hz frequency, and 133 A/mm² current density. The satisfactory agreement in the macroscopic
8 stress-strain comparison and the details shown in the magnified views demonstrate the robustness of the
9 model under different loading conditions.

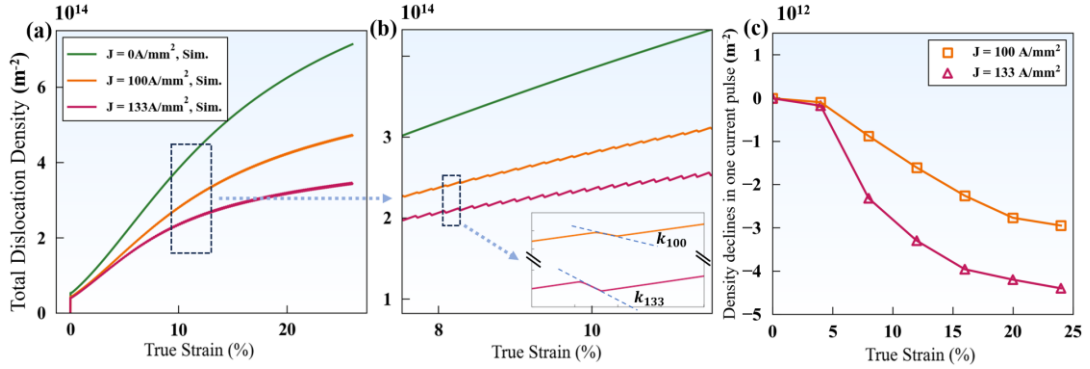
10 4.3. Dislocation density evolutions and grain orientations

11 In this section, simulation results on dislocation density evolutions and corresponding full-field HR-
12 EBSD evaluations are presented, revealing current-induced dislocation recovery. The dislocation density
13 evolutions under pulsing currents feature local fluctuations linked to current intensity and true strain.
14 Analysis on SSDs and GNDs is also incorporated inside for further discussions on grain orientations and
15 previously demonstrated texture results. The total dislocation density evolution is computed via a
16 volume-weighted average of the density within each individual grain.

17 Fig. 13 (a-b) show the simulated dislocation evolutions under three different current densities
18 throughout the deformation. Fig. 13 (a) shows the overall tendency, with significant differences
19 observed that the densities decrease as the applied current increases. Fig. 13 (b) shows an enlarged view
20 for the boxed area inside Fig. 13 (a) for more details: the small fluctuations show the dislocation
21 recovery raised by the applied pulses. The inserted image inside Fig. 13 (b) presents the detail of the
22 boxed area, showing that the amplitude of these fluctuations is positively correlated with the current
23 density. The slopes of the decreasing stages in 100 A/mm² and 133 A/mm² cases are denoted as k_{100} and
24 k_{133} . It is obvious that $k_{133} < k_{100}$, indicating the dislocation recovery in one pulse increases with the
25 applied current density.

26 To quantitatively analyze these “small recoveries”, Fig. 13 (c) provides the amplitude of the
27 recoveries at certain true strain extents. Obviously, the larger the input current density is, the
28 stronger the local recovery is. Besides, the increasing trend indicates that a single current pulse
29 can induce greater dislocation recovery at higher strain extents, where more dislocations are already
present. This trend suggests that the electroplastic effect not only depends on the current density, but
also becomes more

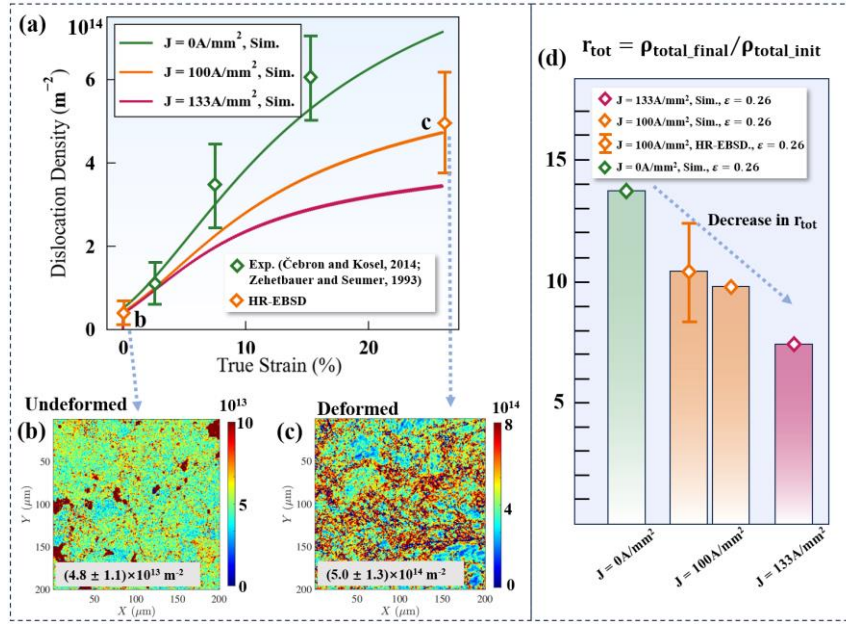
1 pronounced with a higher amount of the stored dislocation density, consistent with prior studies (Bilyk
 2 et al., 2005; Kim et al., 2017).



3
 4 **Fig. 13** (a) Simulated total dislocation density evolution. (b) Enlarged view of the boxed region
 5 showing rises and drops under pulsed currents; inset highlights density declines at different
 6 currents. (c) The plot of dislocation density declines in each pulse period versus true strain under
 7 different current density.

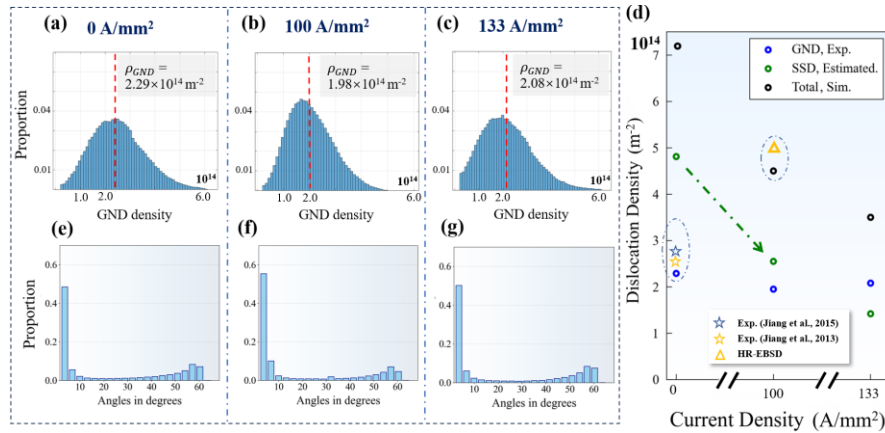
8 To verify the dislocation density recovery magnitude, high-resolution EBSD (HR-EBSD) coupled with
 9 the Williamson-Hall (WH) method (Borbély, 2022) was employed to analyze the dislocation increment
 10 ratio r_{tot} , defined as the ratio between the final total DD and the initial total DD ($r_{\text{tot}} =$
 11 $\rho_{\text{total_final}}/\rho_{\text{total_init}}$). During the r_{tot} evaluation procedure, 4×10^4 Kikuchi patterns recorded by EBSD
 12 experiments are used. The transversal brightness profiles of major Kikuchi bands are extracted (Takeuchi
 13 et al., 2025) and compared with those of simulated diffraction patterns. A dedicated diffraction signal
 14 correlation method is used to characterize the blurriness of the experimental diffraction patterns,
 15 represented by the kernel size of the Gaussian function convolution. The slope of the kernels of
 16 convolution functions is transformed into relative dislocation densities ($r_{\text{tot}} = \rho_{\text{tot_final}}/\rho_{\text{tot_init}}$). The
 17 measured kernel angle misorientation (KAM) values are converted into GNDs densities
 18 ($r_{\text{GND}} = \rho_{\text{GND_final}}/\rho_{\text{GND_init}}$) by methods in (Zhong et al., 2024). Since HR-EBSD provides full-field
 19 measurements, the SSD density can be directly mapped through the subtraction $\rho_{\text{SSD}} = \rho_{\text{tot}} - \rho_{\text{GND}}$
 20 at each pixel. This procedure firstly gives ρ_{GND} and ρ_{tot} (thus r_{GND} and r_{tot}), and yields ρ_{SSD} (thus
 21 r_{SSD}) accordingly.

22 Fig. 14 (a) shows the reported dislocation density evolution along with experimental data from the
 23 literature, showing great consistency with the non-electric case, which validates the simulations in
 24 Section 4.2. (Čebren and Kosel, 2014; Zehetbauer and Seumer, 1993). The initial and deformed
 25 dislocation densities in the case $J = 100 \text{ A/mm}^2$ estimated by HR-EBSD is also provided as orange
 26 markers. The deformed dislocation density is obtained by aligning the initial value to the simulation
 27 configuration and multiplying by the final-to-initial ratio r_{tot} derived from the post-processed EBSD
 28 maps in Fig. 14 (b-c). Error bars reflect the statistical distributions within these maps. Fig. 14 (d) shows
 29 a quantitative comparison of r_{tot} for three simulation cases and one experimental case. Beyond
 30 confirming the prediction-experiment consistency, the results quantitatively demonstrate electricity-
 31 induced dislocation recovery and its dependency on the electric density.



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Fig. 14 (a) For quantitatively illustrating the validation of our dislocation density evolution curve. Presented here are several works on the densities of copper (Čebon and Kosel, 2014; Zehetbauer and Seumer, 1993) and the value measured in our work by HR-EBSD. (b-c) The undeformed and deformed full-field total DD distribution image with mean values indicated. (d) Histogram of $\rho_{\text{total_final}}/\rho_{\text{total_init}}$ comparison of simulation under different current densities (0 A/mm², 100 A/mm² and 133 A/mm²) and HR-EBSD results under 100 A/mm².



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Fig. 15 (a–c) Histograms and average values of GND densities deformed under different pulsed currents. (d) Total dislocation, GND, and estimated SSD densities versus pulsed current; pentagons indicate GND values at the same strain (~26%) from conventional tensile tests (Jiang et al., 2013; Jiang et al., 2015). To avoid ambiguity, each dashed ellipse represents the same value measured or calculated in different methods or studies. (e–g) Stable grain misorientation distributions of samples corresponding to (a–c).

15 In the EC-EVPSC model, a conventional dislocation density-based homogenization framework,
16 GNDs and SSDs are not computed separately; only the total dislocation density is tracked. To identify
17 the individual contributions, the EBSD data in Fig. 8 were converted into GNDs (shown in Fig. 15a–c)
18 using the classical Ashby relation ($\rho_{\text{GND}} = \beta KAM/Lb^\alpha$) (Ashby 1970; Shi 2021) where we take $\beta =$

3 (Konijnenberg et al., 2015) and $L = 1.0 \mu\text{m}$. The simulated SSD was then obtained by subtracting
 2 the GND from the total dislocation density. Fig. 15 (d) presents the total dislocation density, GND, and
 3 SSD at the end of deformation ($\varepsilon = 0.26$) for various current densities. The GND appears largely
 4 unaffected by the applied current across deformation conditions, whereas the SSDs show significant
 5 differences. Notably, SSDs primarily contribute to strength through random pinning (Arsenlis and Parks,
 6 1999), and GNDs are responsible for accommodating lattice curvature (Gao and Huang, 2003) and
 7 driving grain rotation (Liang and Dunne, 2009). Fig. 15 (e-g) show that grain misorientation distributions
 8 of different samples possess no significant difference. This explains the texture results: in copper, the
 9 electroplastic effect primarily incorporates the recovery of SSDs rather than GNDs, thus maintaining a
 10 quasi-stable $\langle 111 \rangle$ //RD fiber intensity.

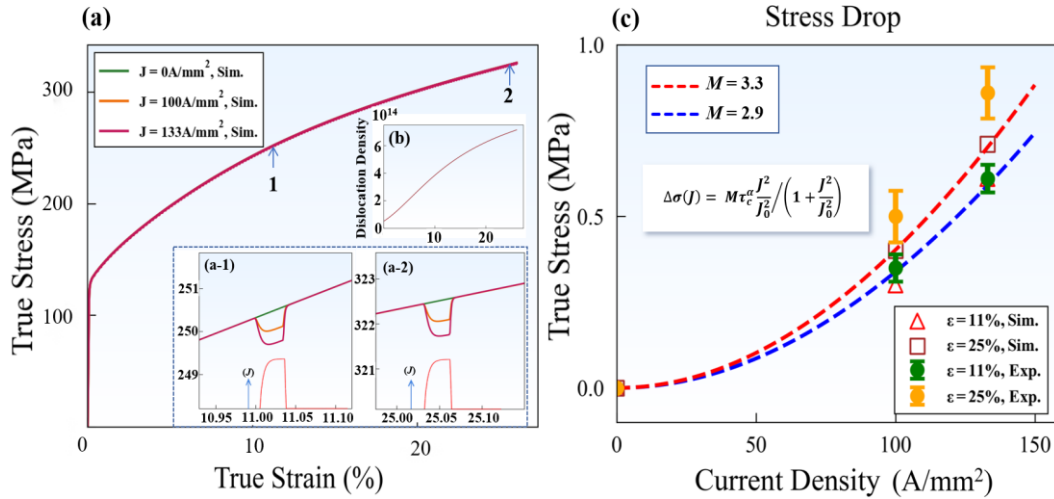
11 4.4. Electro-mechanical coupled mechanisms controlling the overall electroplastic effects

12 Previous studies revealed a two-stage local stress response (“rapid drop” and “slow decline”) linked
 13 to dislocation movements under electro-mechanical coupling. This section examines the mechanisms by
 14 introducing pulsed electricity separately into the Orowan equation and the modified Kocks-Mecking
 15 model, isolating their contributions to the observed responses in experiments and simulations. Note that
 16 this is only a modeling demonstration, with all parameters identical to the $J = 0 \text{ A/mm}^2$ case.

17 Simulations are first performed with dislocation evolution laws disabled (Section 3.3), retaining only
 18 the current-dependent terms in the Orowan equation (Section 3.2) representing short-range barrier
 19 reduction. This mathematical form that only considers EAD’s influence on Orowan equations, also used
 20 in CPFEM studies (Lahiri et al., 2019; Yang et al., 2023a; Zheng and Yi, 2025), shows no clear effect of
 21 current density on the stress-strain envelope (Fig. 16a), aside from local stress fluctuations and “rapid
 22 drops” (Figs. 16a-1, 16a-2). As Fig. 16 (b) indicates, dislocation evolution is unchanged, explaining the
 23 invariant stress-strain envelopes. Thus, the Orowan equation alone explains only the “reversible” stress
 24 reductions in EAD and shows no cumulative effects. However, even without changes in dislocation
 25 density, the stress drops in these cases increase slightly with tensile strain, consistent with experimental
 26 observations. To clarify this behavior, an analysis is conducted on the relationship between current
 27 “density (J) - true strain (ε) – magnitude of rapid stress drop ($\Delta\sigma$)”. This analysis follows prior studies
 28 (Lahiri et al., 2019; Molotskii and Fleurov, 1995) with some mathematical modifications. The
 29 quantitative relationship is given directly below, with justifications in Appendix 2:

$$30 \quad \Delta\sigma(J) = M\tau_c^\alpha \frac{J^2}{J_0^2} \left/ \left(1 + \frac{J^2}{J_0^2} \right) \right. \quad (19)$$

31 where M is the Taylor factor (Lahiri et al., 2019) of the activated slip system. The rapid stress drop ($\Delta\sigma$)
 32 at 11% and 25% strain (Fig. 16 (c)) increases with current and rises slightly with strain. The fitted Taylor
 33 factor increased a little, reflecting the behavior mainly governed by the strengthening of the $\langle 111 \rangle$ //RD
 34 texture (Gao et al., 2022): as more $\{111\}$ plane normals align with the tensile axis, the M increases and
 35 the slip velocity on $\{111\}$ planes becomes higher. At larger strains, maintaining a constant macroscopic
 36 strain rate under sudden current requires greater instantaneous changes in ΔG_0^α and τ_c^α , which enhances
 37 $\Delta\sigma$. Thus, $\Delta\sigma$ scales positively with strain even under same current density. This also implies that in
 38 EAD processes with lower Taylor factors (e.g., torsion, $M \approx 1.7$) or extreme textures (e.g., copper wires),
 39 the electroplastic effect may be different.



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Fig. 16 (a) Stress responses from electricity-coupled dislocation movement under different currents. (a-1, a-2) Enlarged views showing rapid stress drops with normalized current profiles. (b) Dislocation density evolution for three curves, showing no change during deformation under different currents. (c) Stress drops versus current density, compared with theoretical predictions from the Orowan equation and experimental values with error bars.

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Following a discussion on the relationship between “rapid drop” and the electricity-affected Orowan equation, additional simulation cases are conducted without electroplasticity on the Orowan equation (Section 3.2) and with the modified dislocation evolution law activated (Section 3.3). The red markings in the equation of Fig. 17 indicate how current influences the modified Kocks–Mecking relationship. In Fig. 17(b), the stress curve shows the earlier “work-softening” behavior without any rapid drop, and Fig. 17(c) shows dislocation density evolution similar to before, with $\text{sgn}(d\rho/d\gamma)$ from positive to negative rapidly at the rising edge of the pulses. These results clearly show how the electricity affects the dislocation dynamic recovery, therefore providing the “slow decline” phase in the local stress fluctuations. The density declines in each pulse evolving with tensile strain have been discussed in Section 4.4.

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Two points should be noted here. First, the modification of $k_{\rho,mul}$ mathematically corresponds to multiplying the right-hand side of the dislocation evolution law by a factor smaller than 1.0. This alone will not result in a positive to negative change of the $\text{sgn}(d\rho/d\gamma)$ but only lower down the multiplication rate. Second, to reproduce the ‘work-softening’ behavior before and after the applied pulses, as well as dislocation evolution rates of opposite signs, an influence on g^α must be incorporated. The modification of g^α arises from the electron–dislocation scattering mechanism, indicating its dominant role in the electroplastic dislocation dynamic recovery process. This modification is consistent with arguments of previous studies on copper (Dai et al., 2024; Li et al., 2013). On the other hand, even if the modification of g^α is disabled and only $k_{\rho,mul}(J)$ is retained, the decrease in macroscopic work-hardening rate can still be ensured. The second effect explains why some studies (Xu et al., 2022; Zheng and Yi, 2025) can capture changes in macroscopic work-hardening solely by incorporating changes in mean free path length.

Affected effects
in DD evolution

$$\frac{d\rho}{d\gamma} = \left(\frac{k_{\rho, mul}}{\bar{L} \cdot \left(1 + \frac{J^2}{J_0^2}\right)} \right) \left(1 - \left[\frac{c_h b}{g(0)} \left(1 + \frac{J^2}{J_1^2}\right) \left(1 - \frac{kT}{Db^3} \log \frac{|\dot{\epsilon}|}{\dot{\epsilon}_0}\right) \right]^2 \rho \right)$$

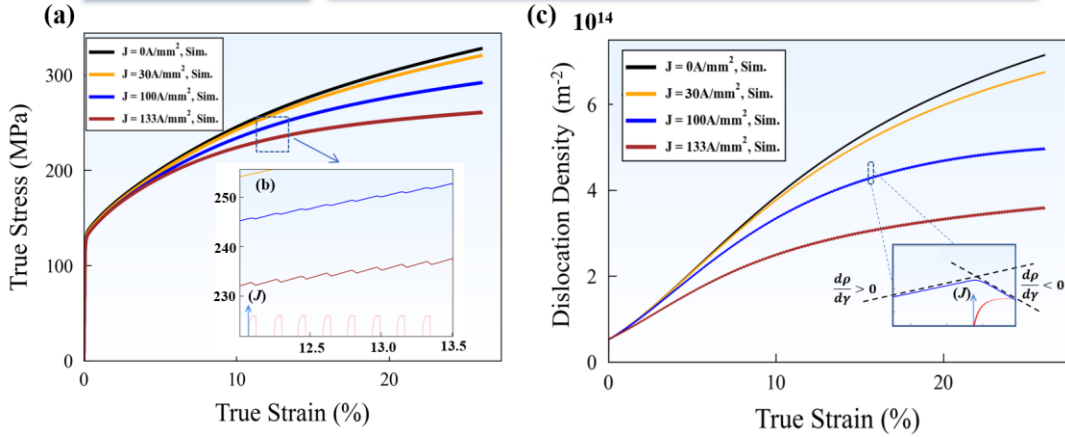


Fig. 17 (a) Stress responses governed by electricity-coupled dislocation evolution under different currents. (b) Enlarged view showing the slow stress drop with increasing current. (c) Dislocation evolution curve with fluctuations induced by periodic electric pulses, showing electric-induced dynamic recovery process.

To make a summary, local fluctuation in stress responses during EAD is divided into three stages (S1–S3, Fig. 18): rapid drop (S1) from short-range barrier reduction (Fig. 18 (b)), dynamic recovery process (S2) via electric-induced dislocation motion (Fig. 18 (c)), and rebound (S3) from new displacement multiplication and reverse of short-range barrier (Fig. 18 (d)). The transition from S1 to S2 occurs at the characteristic time of the current pulse (τ_t). If $\tau_t \rightarrow 0s$, which means a perfect square wave profile, a perfect “instantaneous drop” could be expected. The overall work-hardening arises from the cumulative effect of these stages. However, different FCC metals, even with similar stacking fault energies (e.g., Al vs. Ni), show distinct electroplastic effects (Kim et al., 2017; Liang et al., 2017; Yan et al., 2023; Zhang et al., 2020), indicating that the mechanisms controlling electroplastic effects operate at a finer scale than that at which stacking fault energy, activation energy, and slip resistance are typically defined. More discussions will be presented in Section 4.5.

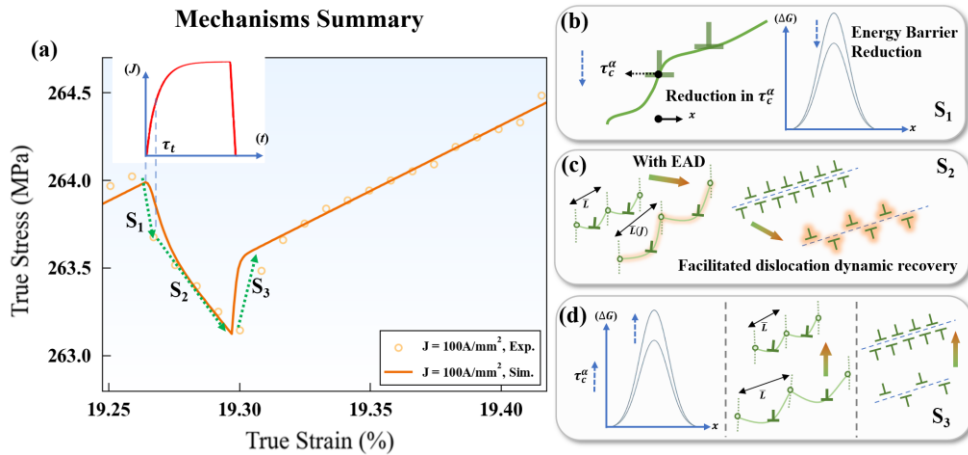


Fig. 18 (a) The 3-stage stress response in a single pulse, with the pulse profile accompanied. (b-d) The schematic figures of the mechanisms in the 3 stages. This abstract for mechanisms highlights the

1 differences between the instantaneous barrier reduction and the subsequent dynamic process.

2 4.5. Revisiting previous studies

3 Building on the above discussion of the key mechanisms of electroplastic effects in copper, several
4 classic studies on electroplasticity warrant revisiting and re-examination, as they may offer new insights
5 into earlier findings.

6 Previous studies on copper under electric-assisted deformation (EAD) have shown reductions in
7 maximum flow stress and work-hardening (He et al., 2020; Xu et al., 2022; Zhang et al., 2018). Our
8 temperature-controlled experiments confirm these findings, with stress-strain curve envelopes and
9 crystal plasticity simulations indicating suppressed dislocation multiplication. For samples with similar
10 grain sizes, (Zhang et al., 2018) reported only minor yield-stress variations under different current
11 densities and our results are consistent with this trend. Current-induced stress drops, long recognized in
12 literature (Li et al., 2013; Silveira et al., 1981; Zhang et al., 2018), are also observed here, providing
13 further evidence of electroplastic stress-strain responses and their relation to dislocation density evolution.
14 In contrast, texture evolution differs from some earlier reports. EBSD studies (Xu et al., 2022) suggested
15 a reduction of $\langle 111 \rangle // \text{RD}$ intensity and $\sim 10\%$ loss of $\langle 111 \rangle$ -oriented grains, but large-area EBSD in the
16 present study reveals no such weakening, implying that earlier conclusions may reflect limited mapping
17 fields. At the dislocation scale, TEM analysis of the $\{100\} \langle 110 \rangle$ system indicates that non-octahedral
18 slip is unlikely to be activated, as evidenced by its low dislocation density, isolated morphology, and the
19 absence of corresponding texture evolution. It has been attributed to Lomer–Cottrell locks, known to
20 contribute to copper’s hardening (Anderson et al., 2017), and does not support the presence of enhanced
21 non-octahedral activity suggested in previous work.

22 Furthermore, new interpretations can be proposed for the counterexample reported by (Rudolf et al.,
23 2021), where copper exhibited electroplastic effects only in maximum elongation but not in work
24 hardening. In that study, EAD tests were carried out under continuous direct current (CDC) conditions
25 at very low strain rates, with loading times of up to 40 minutes before fracture. Notably, before yielding,
26 there was an initial loading period of about one minute, sufficient for CDC to directly annihilate
27 dislocations (Zhang et al., 2020). The yield stress is thus changed. The magnitude of dislocation density
28 annihilated in this process could be roughly estimated by the Taylor relation (Taylor, 1934) that
29 $\Delta\sigma \sim \alpha\mu b\Delta\sqrt{\rho}$. Taking $\alpha \approx 0.4$ (Akhondzadeh et al., 2020; Madec et al., 2002) and $\Delta\sigma = 15$ MPa
30 (Rudolf et al., 2021), this estimation yields a dislocation density change of $\Delta\sqrt{\rho} \approx 3 \times 10^6 \text{ m}^{-1}$. By
31 supposing an initial dislocation density as $\rho_0 = \sum_{\alpha} \rho_0^{\alpha} \approx 10^{14} \text{ m}^{-2}$ (Lei et al., 2025) and noting the real
32 initial density as ρ_{real} , we could have that: $\Delta\sqrt{\rho} = \sqrt{\rho_0} - \sqrt{\rho_{real}} \approx 3 \times 10^6 \text{ m}^{-1}$ and thus $\rho_{real} \approx$
33 $0.5 \times 10^{14} \text{ m}^{-2}$ which accounts for a half of ρ_0 . This magnitude suggests that the electroplastic effects
34 are not significant due to the pre-annihilated dislocations. In addition, starting temperature of TAD
35 loading to compare the $J = 125 \text{ A/mm}^2$ case deviated clearly from the room temperature, showing a
36 possible long pre-loading period with temperature rising and thus initiated dislocation recovery.

37 In addition to conventional experiments, since the 1980s (Silveira et al., 1981), researchers have
38 attempted to eliminate thermal effects in electroplastic experiments using liquid helium or nitrogen, a
39 method still used today (Zhao et al., 2021). One study tested Pb (an FCC metal) (Silveira et al., 1981) at
40 4.2 K during EAD and reported no electroplastic effect, long regarded as evidence that electroplastic

1 arises solely from the Joule effect. This interpretation is flawed. As a Type-I superconductor (Kittel and
 2 McEuen, 2018), Pb follows BCS theory (Bardeen et al., 1957a; Bardeen et al., 1957b), where Cooper
 3 pair formation suppresses electron-lattice scattering, drastically reducing momentum transfer.
 4 Additionally, the Meissner effect (Meissner and Ochsenfeld, 1933) limits magnetic field penetration,
 5 hindering magnetoplastic mechanisms. Later studies (Molotskii, 1995; VA, 1997) highlighted magnetic
 6 field effects, while more recent work (Dai et al., 2024; Lahiri et al., 2019; Li et al., 2013; Niu et al., 2025;
 7 Xu et al., 2022) emphasized electron-dislocation scattering. Thus, the ‘null-electroplastic’ effect likely
 8 reflects an artifact from suppressing mechanisms (electron-dislocation scattering and magnetoplasticity)
 9 of electroplastic under superconductivity.

10 Lastly, another key factor influencing electroplastic effects is the type of metal, as discussed in Section
 11 4.4. For example, the quantitative contribution of electron-dislocation scattering also depends on intrinsic
 12 material properties, as the electron relaxation time τ_{relax} varies across metals and can be expressed
 13 explicitly (Xu et al., 2023).

$$14 \quad \frac{1}{\tau_{relax}} = \frac{1}{\tau_{cry}} + \frac{1}{\tau_{dis}} \quad (20)$$

15 where τ_{cry} and τ_{dis} are the relaxation times for perfect lattices and dislocations depend on the material
 16 type and the atomistic level electronic structure. The energy ΔE transferred by drifting electrons scales
 17 as $\Delta E \propto \tau_{relax}^2$ (Dai et al., 2024; Li et al., 2013). Accordingly, J_1 and J_0 are treated as fitting
 18 parameters to capture material-dependent electroplastic responses. These physical facts highlight the
 19 difficulty of establishing a unified electroplasticity model applicable to all materials. Modeling and
 20 analysis of other FCC metals (e.g., pure aluminum) are beyond the scope of this work and will be reported
 21 separately in another work.

22 5. Conclusions

23 This study provides new experimental and modeling insights into the electroplasticity of copper under
 24 pulsed current EAD loading. The main conclusions can be summarized as follows:

- 25 (1) Temperature-controlled experiments demonstrated pronounced electroplastic effects in copper
 26 subjected to pulsed currents, manifested by significant reductions in maximum tensile stress
 27 and work-hardening rate. These results provide direct evidence of athermal contributions
 28 beyond conventional thermal softening. The stress-strain curves under EAD loading exhibited
 29 characteristic stress fluctuations, with the local response showing “rapid drop” and “slow
 30 decline” phases, in contrast to the smooth profiles in purely mechanical deformation response.
- 31 (2) Large-area EBSD (1000 $\mu\text{m} \times 1000 \mu\text{m}$) and two-beam TEM analyses confirmed that copper
 32 under EAD deforms primarily via conventional $\{111\} \langle 110 \rangle$ slips, with no significant non-
 33 octahedral activation. Textures and grain misorientation distributions for deformed samples in
 34 different EAD cases retained well, indicating slight current-induced orientation changes. HR-
 35 EBSD and EC-EVPSC simulations consistently showed a marked reduction in total dislocation
 36 density under current, mainly from annihilation of statistically stored dislocations (SSDs),
 37 while geometrically necessary dislocations (GNDs) remained nearly stable.
- 38 (3) The EC-EVPSC model successfully reproduced temporal electricity-induced stress-strain
 39 responses, dislocation density evolution, and texture stability, demonstrating strong predictive

1 capability and providing a fast and robust experimental-numerical framework for exploring
 2 electroplastic mechanisms. The satisfactory predictions rely on the necessity of coupling the
 3 electricity-related term with the thermodynamic evolution laws. By addressing the physical
 4 origins, the efficiency of this treatment is highlighted by the fact that only two electricity-
 5 related parameters (J_0 and J_1) are required to capture these complex mechanisms,
 6 distinguishing the present approach from phenomenological fitting.

- 7 (4) The local responses on stress-strain curves could be decoupled into three stages (S1, S2 and
 8 S3), attributed respectively to instantaneous friction barrier drop (S1), promoted dislocation
 9 recovery and changes in mean free paths (S2), and subsequent dislocation multiplications and
 10 barrier recovery (S3). Essentially, the divergence in the stress-strain envelopes and work-
 11 hardening rates represents the collective outcome of these local stress drops stimulated during
 12 EAD experiments.

13 Beyond the specific conclusions, this work highlights a mechanism-focused perspective on
 14 electroplasticity in copper under pulsed-current loading. By integrating established electroplastic
 15 mechanisms within a dislocation-density-based framework, the study enables interpretations of how
 16 athermal contributions influence macroscopic softening. Further semi-quantitative evaluation is achieved
 17 by integrating model predictions with HR-EBSD evidence. This combined approach effectively and
 18 synergistically linked the microscopic mechanisms with observed stress-strain responses, providing a
 19 concise, physics-based understanding that may guide further exploration and modeling of electroplastic
 20 deformation in metals.

21 Appendix 1. The self-consistent scheme of EVPSC model

22 The core mathematics involves volume-weighted averaging of grain-level stretching rate (d_{ij}),
 23 rotation rate (w_{ij}), and Cauchy stress (σ_{ij}) tensors into macroscopic quantities, as shown in Eq. (2).
 24 Here, the capitals indicate corresponding macroscopic quantities (ex. D_{ij} denotes macroscopic stretching
 25 tensor) and lower-case letters represent the grain level ones.

$$27 \quad D_{ij} = D_{ij}^e + D_{ij}^p = \frac{1}{V} \int (d_{ij}^e + d_{ij}^p) dV \quad (A1a)$$

$$28 \quad W_{ij} = W_{ij}^e + W_{ij}^p = \frac{1}{V} \int (w_{ij}^e + w_{ij}^p) dV \quad (A1b)$$

$$29 \quad \Sigma_{ij} = \frac{1}{V} \int \sigma_{ij} dV \quad (A1c)$$

30 The notation e and p denote elastic and plastic parts. The material's elastic behavior relates the
 31 Jaumann rate of the Cauchy stress $\dot{\Sigma}_{kl}^{\nabla}$ and $\dot{\sigma}_{kl}^{\nabla}$ to the elastic stretching rate. The nonlinear viscoplastic
 32 strain rate is expressed pseudo-linearly with stress (Nemat-Nassar et al., 2012), combining with the strain
 33 tensor d_{ij}^0 and D_{ij}^0 :

$$34 \quad D_{ij} = \bar{M}_{ijkl}^e \dot{\Sigma}_{kl}^{\nabla} + \bar{M}_{ijkl}^p \Sigma_{kl} + D_{ij}^0 \quad (A2)$$

$$35 \quad d_{ij} = M_{ijkl}^{e,g} \dot{\sigma}_{kl}^{\nabla} + M_{ijkl}^{p,g} \sigma_{kl} + d_{ij}^0 \quad (A3)$$

36 \bar{M}_{ijkl}^e and \bar{M}_{ijkl}^p are respectively the elastic compliance tensor and plastic compliance (Wang et al.,
 37 2010). The ‘overbar’ indicates the compliance in the polycrystal scale system. The localization
 38 factor B_{ijkl}^g and back stress tensor b_{ij}^g connect the viscoplastic behavior of individual grains to the

1 macroscopic polycrystal response, applicable to both elastic and plastic parts (Wang et al., 2010). The
 2 notation g denotes ‘grain level’.

$$3 \quad \sigma_{ij} = B_{ijkl}^g \Sigma_{kl} + b_{ij}^g \quad (A4)$$

4 The plastic deformation gradient tensor l_{ij}^p in each grain is controlled by dislocation-induced
 5 plasticity and twinning behavior is not included in this study:

$$6 \quad l_{ij}^p = l_{ij}^{dis} \quad (A5)$$

7 Note that the average elastic and plastic compliance $\bar{M}_{ijkl}^{e,p}$ is defined in a polycrystal system but is
 8 not equal to the volume-weighted average. The ‘self-consistent’ process involves solving linear systems
 9 about components of compliance tensors and localization tensors, which could be yielded by substituting
 10 Eqs. (A2)-(A5) into (A1), thus enabling the final solution of multiscale constitutive laws. This approach
 11 is typically faster than CPFEM, as it avoids the need for complex meshing.

12

13 Appendix 2. Estimation of electrically influenced “rapid drop”

14 2.1. Derivation of the quantitative relationship

15 The relationship between “current density (J) - true strain (ϵ) – magnitude of rapid stress drop ($\Delta\sigma$)”
 16 is presented here. This analysis is analogous to the ones in prior research (Lahiri et al., 2019), but with
 17 some differences in mathematical form. We link the bulk plastic behavior to that of an individual grain
 18 through the Taylor factor (M) of the activated slip system and treat the macroscopic and slip level plastic
 19 strain rate as a function of current density: $\dot{\epsilon}_p(J)$ and $\dot{\gamma}^\alpha(J)$, which gives:

$$20 \quad \dot{\epsilon}_p(J) = \frac{1}{M} \sum_{\alpha} \dot{\gamma}^\alpha(J) = \frac{1}{M} \sum_{\alpha} \dot{\gamma}_0^\alpha \exp\left(\frac{-\Delta G^\alpha(J)}{k_B T}\right) \quad (A6)$$

21 where $\Delta G^\alpha(J) = \Delta G_0^\alpha / \left(1 + \frac{J^2}{J_0^2}\right) \left[1 - \frac{\sigma_{eff}(J)/M}{\tau_c^\alpha} \left(1 + \frac{J^2}{J_0^2}\right)\right]$. Here, we neglect the elastic strain rate $\dot{\epsilon}_e$,
 22 with detailed justifications for this neglect in Appendix 2.2. Thus, we suppose that the imposed
 23 loading boundary condition ($\dot{\epsilon}(0) = \dot{\epsilon}(J) = 5 \times 10^{-3} \text{ s}^{-1}$) gives directly that $\dot{\epsilon}_p(0) = \dot{\epsilon}_p(J)$. By imposing
 24 $\dot{\epsilon}_p(0) = \dot{\epsilon}_p(J)$, we get:

$$25 \quad \frac{1}{M} \sum_{\alpha} \dot{\gamma}_0^\alpha \exp\left(\frac{-\Delta G^\alpha(J)}{k_B T}\right) = \frac{1}{M} \sum_{\alpha} \dot{\gamma}_0^\alpha \exp\left(\frac{-\Delta G^\alpha(0)}{k_B T}\right), \quad \forall J > 0, \alpha \in \{1, 2, \dots, 12\}$$

$$\Rightarrow \Delta G^\alpha(0) = \Delta G^\alpha(J) \quad (A7)$$

26 from which we get:

$$27 \quad \Delta G_0^\alpha / \left(1 + \frac{J^2}{J_0^2}\right) \left[1 - \frac{\sigma_{eff}(J)/M}{\tau_c^\alpha} \left(1 + \frac{J^2}{J_0^2}\right)\right] = \Delta G_0^\alpha \left[1 - \frac{\sigma_{eff}(0)/M}{\tau_c^\alpha}\right] \quad (A8)$$

28 From the above expression, we obtain:

$$29 \quad \sigma_{eff}(J) - \sigma_{eff}(0) = -M \tau_c^\alpha \frac{J^2}{J_0^2} / \left(1 + \frac{J^2}{J_0^2}\right) < 0 \quad (A9)$$

30 Eq (A9) actually predicts a stress “drop” upon sudden current excitation due to its negative property.
 31 Here, we define the absolute value of the drop as $\Delta\sigma_{eff} \stackrel{\text{def}}{=} \text{abs}(\sigma_{eff}(J) - \sigma_{eff}(0))$. The $\Delta\sigma_{eff}$ could

1 also be expressed as $\Delta\sigma_{eff} = \Delta\sigma - \Delta\sigma_{friction}$. The equivalent friction stress $\sigma_{friction}$ is defined as:
 2 $\sigma_{friction}(J) \stackrel{\text{def}}{=} M\tau_f = M(\tau_b + \tau_{GB} + c_h Gb\sqrt{\rho_{acc}})$, which is a function of dislocation density and grain
 3 size. Due to no change in dislocation density and grain size in the analysis in Section 4.4, $\Delta\sigma_{friction}(J)$
 4 is imposed to 0 and we get $\Delta\sigma_{eff} = \Delta\sigma(J)$. Thus, we obtain the quantitative relationship between
 5 current density and rapid stress drops, with M related to true strain, noted as $M(\varepsilon)$.

$$6 \quad \Delta\sigma(J) = M(\varepsilon)\tau_c^\alpha \frac{J^2}{J_0^2} \left/ \left(1 + \frac{J^2}{J_0^2} \right) \right. \quad (A10)$$

7 The stress drops at different strains and current densities are analyzed in detail in Section 4.4.

8 2.2 Justifications for neglecting elastic strain rate

9 The total strain rate of uniaxial tension is written as:

$$10 \quad \begin{aligned} \dot{\varepsilon} &= \dot{\varepsilon}_p + \dot{\varepsilon}_e \\ &= \dot{\varepsilon}_p + \frac{\dot{\sigma}}{E} \end{aligned} \quad (A11)$$

11 where $\dot{\sigma}$ is the macroscopic stress rate and E is the macroscopic elastic modulus of copper. Now we
 12 treat the strain rates as functions of J that $\dot{\varepsilon}(J) = \dot{\varepsilon}_p(J) + \dot{\varepsilon}_e(J)$. By applying a sudden change of
 13 current density and imposing the loading boundary condition: $\dot{\varepsilon}(0) = \dot{\varepsilon}(J) = 5 \times 10^{-3} \text{s}^{-1}$, we get:

$$14 \quad \dot{\varepsilon}_p(0) + \frac{\dot{\sigma}(0)}{E} = \dot{\varepsilon}_p(J) + \frac{\dot{\sigma}(J)}{E} \quad (A12)$$

15 Thus,

$$16 \quad \dot{\varepsilon}_p(0) = \dot{\varepsilon}_p(J) + \frac{\dot{\sigma}(J)}{E} - \frac{\dot{\sigma}(0)}{E} = \dot{\varepsilon}_p(J) - \frac{1}{E} [\Delta\dot{\sigma}(J)] \quad (A13)$$

17 where $\Delta\sigma(J) \stackrel{\text{def}}{=} \sigma(0) - \sigma(J)$. As $\Delta\dot{\sigma}(J) = \frac{d\Delta\sigma(J)}{d\varepsilon} \frac{d\varepsilon}{dt} = \frac{d\Delta\sigma(J)}{d\varepsilon} \dot{\varepsilon}$, we then could derive:

$$18 \quad \dot{\varepsilon}_p(0) = \dot{\varepsilon}_p(J) - \frac{1}{E} \frac{d\Delta\sigma(J)}{d\varepsilon} \dot{\varepsilon} \quad (A14)$$

19 Here, the values measured at $\varepsilon_1 = 0.11$ and $\varepsilon_2 = 0.25$ under $J = 100 \text{A/mm}^2$ are applied for
 20 estimation the magnitude of $\frac{1}{E} \frac{d\Delta\sigma(J)}{d\varepsilon}$. We have subsequently:

$$21 \quad \frac{1}{E} \frac{d\Delta\sigma(J)}{d\varepsilon} \sim \frac{1}{E} \frac{\Delta\sigma(J, \varepsilon_2) - \Delta\sigma(J, \varepsilon_1)}{\varepsilon_2 - \varepsilon_1} = \frac{1}{120 \text{GPa}} \frac{0.1 \text{MPa}}{0.14} \sim 10^{-5} \quad (A15)$$

22 This magnitude is extremely small, so, we get that:

$$23 \quad \begin{aligned} \dot{\varepsilon}_p(0) &= \dot{\varepsilon}_p(J) - 10^{-5} \cdot \dot{\varepsilon}(0) \\ &= \dot{\varepsilon}_p(J) - 10^{-5} \cdot (\dot{\varepsilon}_p(0) + \dot{\varepsilon}_e(0)) \\ \Rightarrow \dot{\varepsilon}_p(J) &= \dot{\varepsilon}_p(0) + 10^{-5} \cdot (\dot{\varepsilon}_p(0) + \dot{\varepsilon}_e(0)) \end{aligned} \quad (A16)$$

Conventionally, $\dot{\epsilon}_e$ is smaller than $\dot{\epsilon}_p$ at the plastic deformation stage. By approximation, the assumption adopted in Section 4.4 is verified. The imposed loading boundary condition gives directly:

$$\dot{\epsilon}_p(0) = \dot{\epsilon}_p(J) \quad (A17)$$

Appendix 4. Measurement resolution Analysis

To validate the sufficiency of the real resolution, we employed two independent (see Fig. A1) analysis on the machine noise. The first involved a stress relaxation test (Fig. A1(a)), in which a sample is loaded with the same strain rate ($0.005s^{-1}$) to 400N. Then the strain was maintained. The 2σ of the baseline noise over a 1500 ms window was determined to be 0.031 MPa. The second method utilized the linearity of the work-hardening region (Fig. A1 (b)) on the current-free stress-strain data. By performing a linear fit (strain range: 17.4%–17.9%) and calculating the residual standard deviation (RSD), we obtained a $2 \times RSD$ of 0.035 MPa. These results consistently indicate a resolution on the order of ± 0.03 MPa.

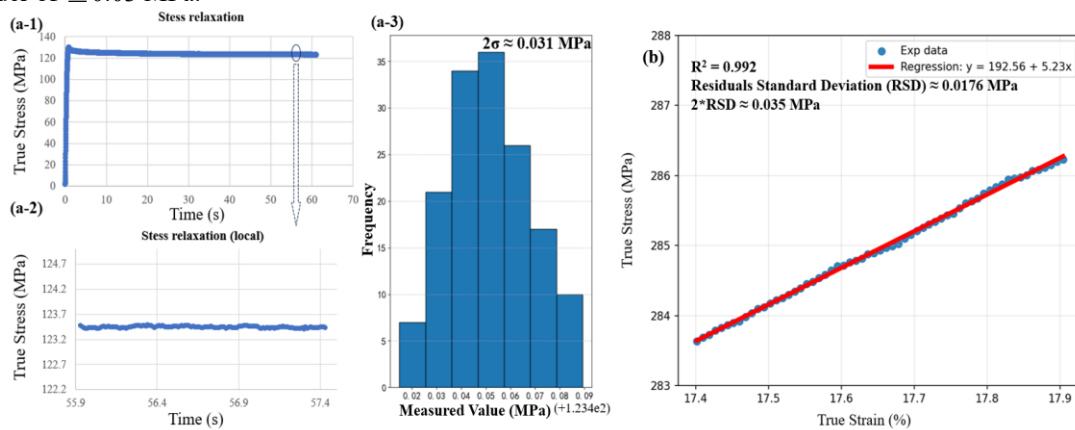


Fig A1. System resolution analysis. (a-1) System noise analysis by stress-relaxation test. (a-2) Magnified stress plateau. (a-3) Statistics of the measured value of the plateau, showing great normal distribution with $2\sigma = 0.031$ MPa. (b) Noise analysis on a segment of the stress-strain curve.

Appendix 5. Additional validation of the model

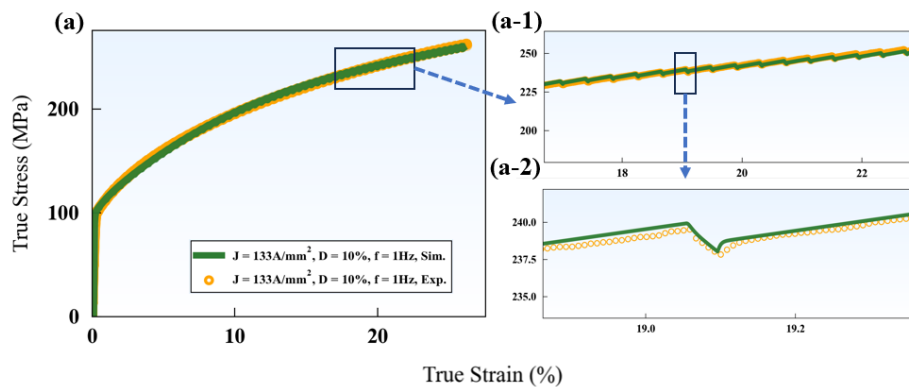


Fig A2. A validation case to further prove the validity of the model. (a) Macroscopic strain-stress comparison. (a-1) and (a-2) Magnified views of the macroscopic strain-stress comparison, showing detailed stress responses accurately captured by the EC-EVPSC model.

1

2 **CRedit authorship contribution statement:**

3 **Kaiwei Wu:** Conceptualization, Data Curation, Formal analysis, Investigation, Methodology, Project
4 Management, Visualization, Writing-original draft, Writing-review & editing. **Xiaochuan Sun:** Software,
5 Formal analysis, Investigation, Methodology, Project Management, Supervision, Writing-review &
6 editing. **Bowen Liu:** Data Curation, Investigation, Methodology, Validation. **Quan Li:** Methodology,
7 Writing-review & editing. **Wei Wen:** Investigation, Writing-review & editing. **Qiwei Shi:** Data Curation,
8 Funding Acquisition, Methodology, Resources, Software, Supervision, Writing-review &
9 editing. **Zhutian Xu:** Resources. **Linfa Peng:** Resources. **Huamiao Wang:** Conceptualization,
10 Supervision, Writing-review & editing. **Yin Zhang:** Validation, Writing - review & editing. **Samuel**
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12

13 **Declaration of competing interest:**

14 The authors declare that they have no known competing financial interests or personal relationships that
15 could have appeared to influence the work reported in this paper.

16

17 **Acknowledgments:**

18 The authors would like to gratefully acknowledge the support of the National Natural Science Foundation
19 of China (Grant No. 52273229). This work is also financially supported by the MAI (Materials Ageing
20 Institute, <http://thema.org>) of France. In addition, the authors would like to gratefully acknowledge
21 State Key Laboratory of Mechanical System and Vibration of Shanghai Jiao Tong University for supports
22 on the experimental electricity source and the EAD platform.

23

24 **Data availability:**

25 Data will be available on request.

26

27 **Reference:**

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